

# IEC60730\_B\_CM33\_Library\_UG\_v4\_0

IEC60730B Library User's Guide



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# Chapter 1

## Core self-test library

The core self-test library provides functions performing the MCU core self-test. The library consists of independent functions performing tests compliant with international standards (IEC 60730, IEC 60335 UL 60730, UL 1998). The library supports the IAR, Keil, and MCUXpresso IDEs. The NXP core self-test library performs the following tests:

- CPU registers test
- CPU program counter test
- Variable memory test
- Invariable memory test
- Stack test
- Clock test
- Digital input/output test
- Analog input/output test
- Watchdog test

The test architecture, implementation, test, and validation of corresponding tests are comprehensively described in independent sections for each test.

The library supports the LPC55Sxx device based on the Arm-M33 core.

The core self-test library has two versions: source code version and object code version. Three object codes (one for each IDE) were compiled from the common source code version. The header files are the same for both versions.

### 1.1 Core self-test library – object code version

The object code version of the library consists of the precompiled binary file and the same list of header files as for the source-code version of the library.

The following are the object files for the given IDEs:

- IAR: *IEC60730B\_CM33\_IAR\_v4\_0.a*
- Keil: *IEC60730B\_CM33\_Keil\_v4\_0.lib*
- MCUXpresso: *libIEC60730B\_CM33\_MCUX\_v4\_0.a*

### 1.2 Core self-test library – source code version

The library name is IEC60730B\_CM33 . The main header files are *iec60730b.h* and *iec60730b\_core.h*.

Each source file (\*.c or \*.S) has a corresponding header (\*.h) file.

**Table 1. List of library items**

File Name	Test Type	Function Name
iec60730b.h	Library header file	-
iec60730b_core.h	Core depend library header file	-
asm_mac_common.h	Common assembler directives	-
iec60730b_aio.c	Analog I/O test	FS_AIO_InputInit()

*Table continues on the next page...*

**Table 1. List of library items (continued)**

File Name	Test Type	Function Name
	Analog I/O test	FS_AIO_InputInit_CYCLIC()
	Analog I/O test	FS_AIO_InputInit_LPC_ADC16()
	Analog I/O test	FS_AIO_InputInit_LPC_ADC12()
	Analog I/O test	FS_AIO_InputTrigger()
	Analog I/O test	FS_AIO_InputSet()
	Analog I/O test	FS_AIO_InputSet_K3S()
	Analog I/O test	FS_AIO_InputSet_CYCLIC()
	Analog I/O test	FS_AIO_InputSet_LPC8XX()
	Analog I/O test	FS_AIO_InputSet_LPC55SXX()
	Analog I/O test	FS_AIO_InputCheck()
	Analog I/O test	FS_AIO_InputCheck_KE()
	Analog I/O test	FS_AIO_InputCheck_K3S()
	Analog I/O test	FS_AIO_InputCheck_CYCLIC()
	Analog I/O test	FS_AIO_InputCheck_LPC8XX()
	Analog I/O test	FS_AIO_InputCheck_LPC55SXX()
iec60730b_clock.c	Clock test	FS_CLK_Check()
	Clock test	FS_CLK_Init()
	Clock test	FS_CLK_LPTMR()
	Clock test	FS_CLK_RTC()
	Clock test	FS_CLK_GPT()
	Clock test	FS_CLK_WKT_LPC()
	Clock test	FS_CLK_TIMER_LPC()
iec60730b_dio.c	Digital I/O test	FS_DIO_Input()
	Digital I/O test	FS_DIO_Output()
	Digital I/O test	FS_DIO_Output_RT()
	Digital I/O test	FS_DIO_Output_LPC()
iec60730b_dio_ext.c	Extended Digital I/O test	FS_DIO_InputExt()
	Extended Digital I/O test	FS_DIO_ShortToSupplySet()
	Extended Digital I/O test	FS_DIO_ShortToAdjSet()
	Extended Digital I/O test	FS_DIO_InputExt_RT()
	Extended Digital I/O test	FS_DIO_ShortToAdjSet_RT()
	Extended Digital I/O test	FS_DIO_InputExt_LPC()

*Table continues on the next page...*

**Table 1. List of library items (continued)**

File Name	Test Type	Function Name
	Extended Digital I/O test	FS_DIO_ShortToSupplySet_LPC()
	Extended Digital I/O test	FS_DIO_ShortToAdjSet_LPC()
iec60730b_cm33_flash.S	Invariable memory test (Flash)	FS_CM33_FLASH_HW16()
	Invariable memory test (Flash)	FS_CM33_FLASH_HW32()
	Invariable memory test (Flash)	FS_CM33_FLASH_SW16()
	Invariable memory test (Flash)	FS_CM33_FLASH_SW32()
iec60730b_cm33_pc.S	Program Counter test	FS_CM33_PC_Test()
iec60730b_cm33_pc_object.S	Program Counter test	FS_PC_Object()
iec60730b_cm33_ram.S	Variable memory test (RAM)	FS_CM33_RAM_AfterReset()
	Variable memory test (RAM)	FS_CM33_RAM_Runtime()
	Variable memory test (RAM)	FS_CM33_RAM_CopyToBackup()
	Variable memory test (RAM)	FS_CM33_RAM_CopyFromBackup()
	Variable memory test (RAM)	FS_CM33_RAM_SegmentMarchC()
	Variable memory test (RAM)	FS_CM33_RAM_SegmentMarchX()
iec60730b_cm33_reg.S	Register test	FS_CM33_CPU_Register()
	Register test	FS_CM33_CPU_NonStackedRegister()
	Register test	FS_CM33_CPU_Primask_S()
	Register test	FS_CM33_CPU_Primask_NS()
	Register test	FS_CM33_CPU_SPmain_S()
	Register test	FS_CM33_CPU_SPmain_NS()
	Register test	FS_CM33_CPU_SPmain_Limit_S()
	Register test	FS_CM33_CPU_SPmain_Limit_NS()
	Register test	FS_CM33_CPU_SPprocess_S()
	Register test	FS_CM33_CPU_SPprocess_NS()
	Register test	FS_CM33_CPU_SPprocess_Limit_S()
	Register test	FS_CM33_CPU_SPprocess_Limit_NS()
	Register test	FS_CM33_CPU_Control_S()
	Register test	FS_CM33_CPU_Control_NS()
	Register test	FS_CM33_CPU_ControlFpu_S()
	Register test	FS_CM33_CPU_ControlFpu_NS()
	Register test	FS_CM33_CPU_Special8PriorityLevels_S()
	Register test	FS_CM33_CPU_Special8PriorityLevels_NS()

*Table continues on the next page...*

**Table 1. List of library items (continued)**

File Name	Test Type	Function Name
iec60730b_cm33_reg_fpu.S	Register test	FS_CM33_CPU_Float1()
	Register test	FS_CM33_CPU_Float2()
iec60730b_cm33_stack.S	Stack test	FS_CM33_STACK_Init()
	Stack test	FS_CM33_STACK_Test()
iec60730b_wdg.c	Watchdog test	FS_WDOG_Setup()
	Watchdog test	FS_WDOG_Check()
	Watchdog test	FS_WDOG_Setup_KE0XZ()
	Watchdog test	FS_WDOG_Check_KE0XZ()
	Watchdog test	FS_WDOG_Setup_COP()
	Watchdog test	FS_WDOG_Setup_KE1XZ()
	Watchdog test	FS_WDOG_Check_KE1XZ()
	Watchdog test	FS_WDOG_Setup_KE1XF()
	Watchdog test	FS_WDOG_Check_KE1XF()
	Watchdog test	FS_CM0_WDOG_Setup_K32W()
	Watchdog test	FS_CM0_WDOG_Check_K32W()
	Watchdog test	FS_CM4_WDOG_Setup_K32W()
	Watchdog test	FS_CM4_WDOG_Check_K32W()
	Watchdog test	FS_WDOG_Setup_RT()
	Watchdog test	FS_WDOG_Check_RT()
	Watchdog test	FS_WDOG_Setup_WWDT_LPC()
Watchdog test	FS_WDOG_Setup_WWDT_LPC_mrt()	
Watchdog test	FS_WDOG_Check_WWDT_LPC()	
Watchdog test	FS_WDOG_Check_WWDT_LPC55SXX()	

## 1.2.1 LPC55Sxx dedicated functions

The following table shows the list of functions dedicated for the LPC55Sxx device family.

**Table 2. LPC55Sxx dedicated functions**

File	Suitable function	Functions size	Functions duration[ $\mu$ S]
iec60730b_aio.c	<a href="#">FS_AIO_InputInit_LPC_ADC16()</a>	29 bytes <sup>1</sup>	0.73 <sup>1</sup>
	<a href="#">FS_AIO_InputTrigger()</a>	12 bytes <sup>1</sup>	0.16 <sup>1</sup>
	<a href="#">FS_AIO_InputSet_LPC55SXX()</a>	36 bytes <sup>1</sup>	0.68 <sup>1</sup>
	<a href="#">FS_AIO_InputCheck_LPC55SXX()</a>	120 bytes <sup>1</sup>	0.53 <sup>1</sup>

*Table continues on the next page...*

Table 2. LPC55Sxx dedicated functions (continued)

File	Suitable function	Functions size	Functions duration[ $\mu$ S]
iec60730b_clock.c	<a href="#">FS_CLK_Check()</a>	38 bytes <sup>1</sup>	0.33 <sup>1</sup>
	<a href="#">FS_CLK_Init()</a>	8 bytes <sup>1</sup>	0.14 <sup>1</sup>
	<a href="#">FS_CLK_WKT_LPC()</a>	TBD bytes <sup>1</sup>	TBD <sup>1</sup>
	<a href="#">FS_CLK_CTIMER_LPC()</a>	24 bytes <sup>1</sup>	12.04 <sup>1</sup>
iec60730b_dio.c	<a href="#">FS_DIO_Output_LPC()</a>	128 bytes <sup>1</sup>	15.59 <sup>1</sup>
iec60730b_dio_ext.c	<a href="#">FS_DIO_InputExt_LPC()</a>	150 bytes <sup>1</sup>	1.62 <sup>1</sup>
	<a href="#">FS_DIO_ShortToSupplySet_LPC()</a>	110 bytes <sup>1</sup>	1.17 <sup>1</sup>
	<a href="#">FS_DIO_ShortToAdjSet_LPC()</a>	184 bytes <sup>1</sup>	1.83 <sup>1</sup>
iec60730b_wdg.c	<a href="#">FS_WDOG_Setup_WWDT_LPC()</a>	52 bytes <sup>1</sup>	-
	<a href="#">FS_WDOG_Check_WWDT_LPC55SX X()</a>	72 bytes <sup>1</sup>	1
iec60730b_flash.S	Function are described in dedicated chapter	See the function dedicated chapter	
iec60730b_pc.S	Functions are common for all CM33 devices	See the function dedicated chapter	
iec60730b_ram.S	Functions are common for all CM33 devices	See the function dedicated chapter	
iec60730b_reg.S	Functions are common for all CM33 devices	See the function dedicated chapter	
iec60730b_stack.S	Functions are common for all CM33 devices	See the function dedicated chapter	

## 1.3 Functions performance measurement

This section contains remarks about the functions' informative size and approximate time of execution. The numbers in the following list are used as remark links from the corresponding sections.

1. The function parameter was measured in the IAR 8.40.1. IDE on LPC55S69 with a clock frequency of 96 MHz.

# Chapter 2

## Analog Input/Output (IO) test

The analog IO test procedure performs the plausibility check of the digital IO interface of the processor. The analog IO test can be performed once after the MCU reset and also during runtime.

The identification of a safety error is ensured by the specific FAIL return if an analog IO error occurs. Compare the return value of the test function with the expected value. If it is equal to the FAIL return, then a jump into the safety error handling function occurs. The safety error handling function may be specific to the application and it is not a part of the library. The main purpose of this function is to put the application into a safety state.

The principle of the analog IO test is based on sequence execution, where a certain analog level is connected to a defined analog input. The test function checks whether the converted value is within the tolerance. The test checks the analog input interface and three reference values: reference high, reference low, and bandgap voltage. See the device specification document to set up the correct values. The block diagram for the analog IO test is shown in the following figure:

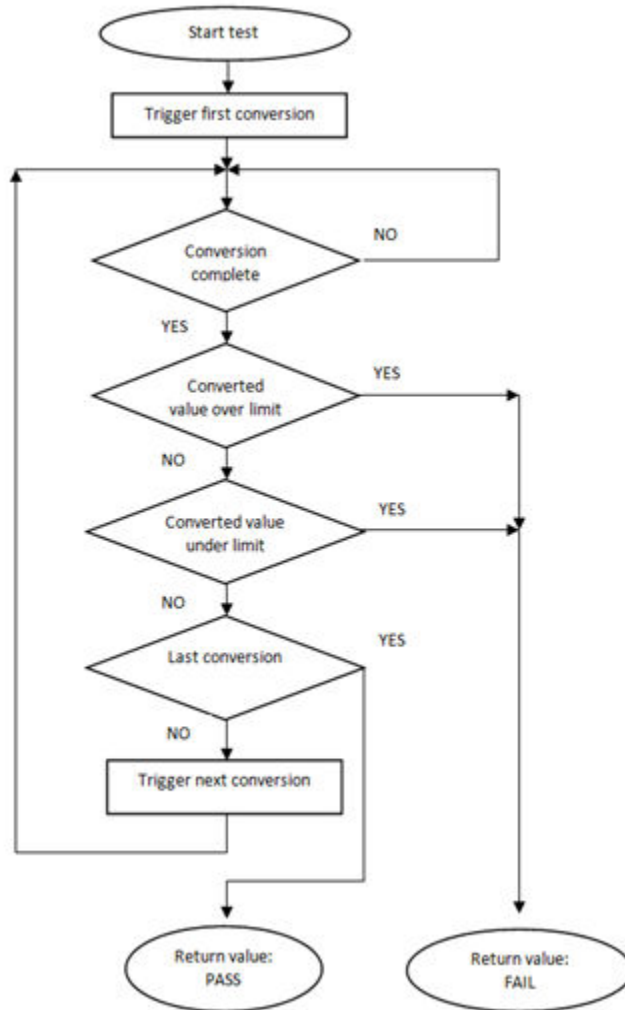


Figure 1. Block diagram for analog input test



## 2.1 Analog input/output test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to the IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

**Table 3. Analog input/output test in compliance with IEC and UL standards**

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
Input/Output periphery	7. Input/Output periphery (7.2 – A/D conversion)	Abnormal operation	B/R.1	Plausibility check

## 2.2 Analog input/output test implementation

The test functions for the analog IO test are placed in the *iec60730b\_aio.c* file and written as "C" functions. The header file with the function prototypes is *iec60730b\_aio.h*. *iec60730b.h* is the common header file for the safety library.

The following functions are called to test the analog input:

- *FS\_AIO\_InputInit()* / *FS\_AIO\_InputInit\_K3SW()* / *FS\_AIO\_InputInit\_CYCLIC()* / *FS\_AIO\_InputInit\_LPC\_ADC16()* / *FS\_AIO\_InputInit\_LPC\_ADC12()* /
- *FS\_AIO\_InputTrigger()*
- *FS\_AIO\_InputSet()* / *FS\_AIO\_InputSet\_K3S()* / *FS\_AIO\_InputSet\_CYCLIC()* / *FS\_AIO\_InputSet\_LPC8XX()* / *FS\_AIO\_InputSet\_LPC55SXX()*
- *FS\_AIO\_InputCheck()* / *FS\_AIO\_InputCheck\_KE()* / *FS\_AIO\_InputCheck\_K3S()* / *FS\_AIO\_InputCheck\_CYCLIC()* / *FS\_AIO\_InputCheck\_LPC8XX()* / *FS\_AIO\_InputCheck\_LPC55SXX()*

The analog input test is based on a conversion of three analog inputs with known voltage values and checks if the converted values fit into the specified limits. Normally, the limits should be about 10 % around the desired reference values. The test is triggered by the *FS\_AIO\_InputTrigger()* function. The test is divided into three parts: initialization, test execution, and the end of the test.

Throughout all supported devices, the ADC module has a slightly different arrangement of the registers that are involved in the test. Therefore, a standalone check function is created for the ADC module. See [Core self-test library – source code version](#) for the function dedicated for your device.

The following is an example of a function call:

### Configuration of parameters

```
#define TESTED_ADC ADC0
#define ADC_RESOLUTION 12
#define ADC_MAX ((1<<(ADC_RESOLUTION))-1)
#define ADC_REFERENCE 3.06
#define ADC_BANDGAP_LEVEL 1.7
#define ADC_BANDGAP_LEVEL_RAW (((ADC_BANDGAP_LEVEL)*(ADC_MAX))/(ADC_REFERENCE))
#define ADC_DEVIATION_PERCENT 10
#define ADC_MIN_LIMIT(val) (((val) * (100 - ADC_DEVIATION_PERCENT)) / 100)
#define ADC_MAX_LIMIT(val) (((val) * (100 + ADC_DEVIATION_PERCENT)) / 100)
#define FS_CFG_AIO_CHANNELS_CNT 3
#define FS_CFG_AIO_CHANNELS_LIMITS_INIT1
```

```

{
  {ADC_MIN_LIMIT(0), ADC_MAX_LIMIT(10)}, |
  {ADC_MIN_LIMIT(ADC_MAX), ADC_MAX_LIMIT(ADC_MAX)}, |
  {ADC_MIN_LIMIT(ADC_BANDGAP_LEVEL_RAW), ADC_MAX_LIMIT(ADC_BANDGAP_LEVEL_RAW)}|
}
#define FS_CFG_AIO_CHANNELS_INIT {30, 29, 27}

```

**Variables definition**

```

fs_aio_test_t aio_Str;
fs_aio_limits_t FS_ADC_Limits[FS_CFG_AIO_CHANNELS_CNT] = FS_CFG_AIO_CHANNELS_LIMITS_INIT;
unsigned char FS_ADC_inputs[FS_CFG_AIO_CHANNELS_CNT] = FS_CFG_AIO_CHANNELS_INIT;

```

**Initialization of the test**

```

FS_AIO_InputInit(&aio_Str, (fs_aio_limits_t*)FS_ADC_Limits, (unsigned char*)FS_ADC_inputs,
FS_CFG_AIO_CHANNELS_CNT);
FS_AIO_InputTrigger(&aio_Str);

```

**The test**

```

for(uint8_t i=0;i<4;i++)
{
  psSafetyCommon->AIO_test_result = FS_AIO_InputCheck(&aio_Str, (unsigned long*)TESTED_ADC);
  switch(psSafetyCommon->AIO_test_result)
  {
    case FS_AIO_START:
      FS_AIO_InputSet(&aio_Str, (unsigned long*)TESTED_ADC);
      break;
    case FS_AIO_FAIL:
      psSafetyCommon->ui32SafetyErrors |= AIO_TEST_ERROR;
      SafetyErrorHandling(psSafetyCommon);
      break;
    case FS_AIO_INIT:
      FS_AIO_InputTrigger(&aio_Str);
      break;
    case FS_AIO_PASS:
      FS_AIO_InputTrigger(&aio_Str);
      break;
    default:
      __asm("NOP");
  }
}

```

```

break;
}
}

```

## 2.2.1 FS\_AIO\_InputTrigger()

This function sets up the analog input test to start the execution of the test (sets state FS\_AIO\_START for pObj).

### **Function prototype:**

```
void FS_AIO_InputTrigger(fs_aio_test_t *pObj);
```

### **Function inputs:**

*\*pObj* - The input argument is the pointer to the analog test instance.

### **Function output:**

*void*

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.2 FS\_AIO\_InputInit()

This function initializes one instance of the analog input test.

### **Function prototype:**

```
void FS_AIO_InputInit(fs_aio_test_t *pObj, fs_aio_limits_t *pLimits, uint8_t *pInputs, uint8_t cntMax);
```

### **Function inputs:**

*\*pObj* - The input argument is the pointer to the analog test instance.

*\*pLimits* - The input argument is the pointer to the array of limits used in the test.

*\*pInputs* - The input argument is the pointer to the array of input numbers used in the test.

*\*cntMax* - The input argument is the size of the input and the limits arrays.

### **Function output:**

*void*

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.3 FS\_AIO\_InputInit\_CYCLIC()

This function initializes an instance of the analog input test.

### **Function prototype:**

```
void FS_AIO_InputInit_CYCLIC(fs_aio_test_t *pObj, fs_aio_limits_t *pLimits, uint8_t *pInputs, uint8_t *pSamples, uint8_t cntMax);
```

### **Function inputs:**

*\*pObj* - The input argument is the pointer to the analog test instance.

*\*pLimits* - The input argument is the pointer to the array of limits used in the test.

*\*pInputs* - The input argument is the pointer to the array of input numbers used in the test.

*\*pSamples* - The input argument is the pointer to the array of sample numbers used in the test.

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*cntMax* - The input argument is the size of the input and the limits arrays.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.4 FS\_AIO\_InputInit\_K3S()

This function initializes an instance of the analog input test.

**Function prototype:**

```
void FS_AIO_InputInit_K3S(fs_aio_test_t *pObj, fs_aio_limits_t *pLimits, uint8_t *pInputs, uint8_t cntMax, uint8_t cmdBuffer);
```

**Function inputs:**

*\*pObj* - The input argument is the pointer to the analog test instance.

*\*pLimits* - The input argument is the pointer to the array of limits used in the test.

*\*pInputs* - The input argument is the pointer to the array of input numbers used in the test.

*cntMax* - The input argument is the size of the input and the limits arrays.

*cmdBuffer* - Specifies the command buffer for the conversion. Has effect only in case of k3s devices.

**Function output:**

*void*

**Function performance:**

Information about function performance is mentioned in the chapter [Core self-test library – source code version](#)

## 2.2.5 FS\_AIO\_InputInit\_LPC\_ADC16()

This function initializes an instance of the analog input test.

**Function prototype:**

```
void FS_AIO_InputInit_LPC_ADC16(fs_aio_test_t *pObj, fs_aio_limits_t *pLimits, uint8_t *pInputs, uint8_t cntMax, uint8_t sequence, uint8_t fifo);
```

**Function inputs:**

*\*pObj* - The input argument is the pointer to the analog test instance.

*\*pLimits* - The input argument is the pointer to the array of limits used in the test.

*\*pInputs* - The input argument is the pointer to the array of input numbers used in the test.

*cntMax* - The input argument is the size of the input and the limits arrays.

*sequence* - No effect, just because of compatibility.

*fifo* - The index of the used FIFO for result.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.6 FS\_AIO\_InputInit\_LPC\_ADC12()

This function initializes an instance of the analog input test.

### Function prototype:

```
void FS_AIO_InputInit_LPC_ADC12(fs_aio_test_t *pObj, fs_aio_limits_t *pLimits, uint8_t *pInputs, uint8_t cntMax, uint8_t sequence);
```

### Function inputs:

*\*pObj* - The input argument is the pointer to the analog test instance.

*\*pLimits* - The input argument is the pointer to the array of limits used in the test.

*\*pInputs* - The input argument is a pointer to the array of input numbers used in the test.

*cntMax* - The input argument is the size of the input and the limits arrays.

*sequence* - The input argument is the index of the sequence used.

### Function output:

*void*

### Function performance:

The Information about the function performance is in [Core self-test library – source code version](#).

## 2.2.7 FS\_AIO\_InputSet()

This function executes the first part of the AIO test sequence. This part sets up the ADC input channel. When the ADC converter is configured for a software trigger, this function also triggers the conversion. The state is changed to FS\_AIO\_PROGRESS. This function can be called when the ADC module is idle and ready for the next conversion.

### Function prototype:

```
FS_RESULT FS_AIO_InputSet(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### Function inputs:

*\*pObj* - The input argument is the pointer to the analog test instance.

*\*pAdc* - The input argument is the pointer to the analog converter.

### Function output:

```
typedef uint32_t FS_RESULT;
```

- *FS\_AIO\_PROGRESS* - A required return value. It means that the input is set.

If any other value is returned, the function has no effect.

### Function performance:

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.8 FS\_AIO\_InputSet\_CYCLIC()

This function executes the first part of the AIO test sequence. This part sets up the ADC input channel. When the ADC converter is configured for a software trigger, this function also triggers the conversion. The state is changed to FS\_AIO\_PROGRESS. This function can be called when the ADC module is idle and ready for the next conversion.

### Function prototype:

```
FS_RESULT FS_AIO_InputSet_CYCLIC(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### Function inputs:

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*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_AIO\_PROGRESS* - The required return value. It means that the input is set.

If any other value is returned, the function has no effect.

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.9 FS\_AIO\_InputSet\_K3S()

This function executes the first part of the AIO test sequence. This part sets up the ADC input channel. When the ADC converter is configured for a software trigger, this function also triggers the conversion. The state is changed to *FS\_AIO\_PROGRESS*. This function can be called when the ADC module is idle and ready for the next conversion.

**Function prototype:**

*FS\_RESULT FS\_AIO\_InputSet\_K3S(fs\_aio\_test\_t \*pObj, uint32\_t \*pAdc);*

**Function inputs:**

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_AIO\_PROGRESS* - The required return value. It means that the input is set.

If any other value is returned, the function has no effect.

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.10 FS\_AIO\_InputSet\_LPC8XX()

This function executes the first part of the AIO test sequence. This part sets up the ADC input channel. When the ADC converter is configured for a software trigger, this function also triggers the conversion. The state is changed to *FS\_AIO\_PROGRESS*. This function can be called when the ADC module is idle and ready for the next conversion.

**Function prototype:**

*FS\_RESULT FS\_AIO\_InputSet\_LPC8XX(fs\_aio\_test\_t \*pObj, uint32\_t \*pAdc);*

**Function inputs:**

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_AIO\_PROGRESS* - The required return value. It means that the input is set.

If any other value is returned, the function has no effect.

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.11 FS\_AIO\_InputSet\_LPC55SXX()

This function executes the first part of the AIO test sequence. This part sets up the ADC input channel. When the ADC converter is configured for a software trigger, this function also triggers the conversion. The state is changed to FS\_AIO\_PROGRESS. This function can be called when the ADC module is idle and ready for the next conversion.

### Function prototype:

```
FS_RESULT FS_AIO_InputSet_LPC55SXX(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### Function inputs:

\*pObj- The input argument is the pointer to the analog test instance.

\*pAdc- The input argument is the pointer to the analog converter.

### Function output:

```
typedef uint32_t FS_RESULT;
```

- FS\_AIO\_PROGRESS - The required return value. It means that the input was set.

If any other value is returned, the function has no effect.

### Function performance:

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.12 FS\_AIO\_InputCheck()

This function executes the second part of the AIO test sequence. This part reads the converted analog value and checks if the value fits into the predefined limits. This function reads the converted value only if pObj->state == FS\_AIO\_PROGRESS. The test is finished when this function reports FS\_AIO\_PASS or FS\_AIO\_FAIL.

### Function prototype:

```
FS_RESULT FS_AIO_InputCheck(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### Function inputs:

\*pObj- The input argument is the pointer to the analog test instance.

\*pAdc- The input argument is the pointer to the analog converter.

### Function output:

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS - A successful execution of the test (all channels tested).
- FS\_FAIL\_AIO - The converted value does not fit into the limits.
- FS\_AIO\_START - A successful conversion and a setup input for the next conversion.
- FS\_AIO\_PROGRESS - The input is not converted yet.
- FS\_AIO\_INIT - The function has no effect.

### Function performance:

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.13 FS\_AIO\_InputCheck\_CYCLIC()

This function executes the second part of the AIO test sequence. This part reads the converted analog value and checks if the value fits into the predefined limits. This function reads the converted value only if `pObj->state == FS_AIO_PROGRESS`. The test is finished when this function reports `FS_AIO_PASS` or `FS_AIO_FAIL`.

### **Function prototype:**

```
FS_RESULT FS_AIO_InputCheck_CYCLIC(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### **Function inputs:**

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

### **Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS* - A successful execution of the test (all channels tested).
- *FS\_FAIL\_AIO* - The converted value does not fit into the limits.
- *FS\_AIO\_START* - A successful conversion and a setup input for the next conversion.
- *FS\_AIO\_PROGRESS* - The input is not converted yet.
- *FS\_AIO\_INIT* - The function has no effect.

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.14 FS\_AIO\_InputCheck\_K3S()

This function executes the second part of the AIO test sequence. This part reads the converted analog value and checks if the value fits into the predefined limits. This function reads the converted value only if `pObj->state == FS_AIO_PROGRESS`. The test is finished when this function reports `FS_AIO_PASS` or `FS_AIO_FAIL`. It is dedicated for 12-bit low-power ADCs.

### **Function prototype:**

```
FS_RESULT FS_AIO_InputCheck_K3S(fs_aio_test_t *pObj, uint32_t *pAdc, uint32_t resFifo);
```

### **Function inputs:**

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

*resFifo* - A 32-bit value of the RESFIFO register.

### **Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS* - A successful execution of the test (all channels tested).
- *FS\_FAIL\_AIO* - The converted value does not fit into the limits.
- *FS\_AIO\_START* - A successful conversion and a setup input for the next conversion.
- *FS\_AIO\_PROGRESS* - The input is not converted yet.
- *FS\_AIO\_INIT* - The function has no effect.

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).



## 2.2.15 FS\_AIO\_InputCheck\_KE()

This function executes the second part of the AIO test sequence. This part reads the converted analog value and checks if the value fits into the predefined limits. This function reads the converted value only if `pObj->state == FS_AIO_PROGRESS`. The test is finished, when this function reports `FS_AIO_PASS` or `FS_AIO_FAIL`.

### Function prototype:

```
FS_RESULT FS_AIO_InputCheck_KE(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### Function inputs:

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

### Function output:

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*- A successful execution of the test (all channels tested).
- *FS\_FAIL\_AIO*- The converted value does not fit into the limits.
- *FS\_AIO\_START*- A successful conversion and a setup input for the next conversion.
- *FS\_AIO\_PROGRESS*- The input is not converted yet.
- *FS\_AIO\_INIT*- The function has no effect.

### Function performance:

The information about the function performance is in [Core self-test library – source code version](#).

## 2.2.16 FS\_AIO\_InputCheck\_LPC55SXX()

This function executes the second part of the AIO test sequence. This part reads the converted analog value and checks if the value fits into the predefined limits. This function reads the converted value only if `pObj->state == FS_AIO_PROGRESS`. The test is finished when this function reports `FS_AIO_PASS` or `FS_AIO_FAIL`.

### Function prototype:

```
FS_RESULT FS_AIO_InputCheck_LPC55SXX(fs_aio_test_t *pObj, uint32_t *pAdc);
```

### Function inputs:

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

### Function output:

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*- A successful execution of the test (all channels tested).
- *FS\_FAIL\_AIO*- The converted value does not fit into the limits.
- *FS\_AIO\_START*- A successful conversion and a setup input for the next conversion.
- *FS\_AIO\_PROGRESS*- The input is not converted yet.
- *FS\_AIO\_INIT*- The function has no effect.

### Function performance:

The Information about the function performance is in [Core self-test library – source code version](#).

## 2.2.17 FS\_AIO\_InputCheck\_LPC8XX()

This function executes the second part of the AIO test sequence. This part reads the converted analog value and checks if the value fits into the predefined limits. This function reads the converted value only if `pObj->state == FS_AIO_PROGRESS`. The test is finished when this function reports `FS_AIO_PASS` or `FS_AIO_FAIL`.

### **Function prototype:**

```
FS_RESULT FS_AIO_InputCheck_LPC8XX(fs_aio_test_t* pObj, uint32_t *pAdc);
```

### **Function inputs:**

*\*pObj*- The input argument is the pointer to the analog test instance.

*\*pAdc*- The input argument is the pointer to the analog converter.

### **Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS* - A successful execution of the test (all channels tested).
- *FS\_FAIL\_AIO* - The converted value does not fit into the limits.
- *FS\_AIO\_START* - A successful conversion and a setup input for the next conversion.
- *FS\_AIO\_PROGRESS* - The input is not converted yet.
- *FS\_AIO\_INIT* - The function has no effect.

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## Chapter 3

# Clock test

The clock test procedure tests the clock frequency of the processor for the "stuck-at" condition. The clock test can be performed once after the MCU reset and also during runtime.

The identification of a safety error is ensured by the specific FAIL return in case of a clock fault. Assess the return value of the test function. If it is equal to the FAIL return, then a jump into the safety error handling function should occur. The safety error handling function is specific to the application and it is not a part of the library. The main purpose of this function is to put the application into a safety state.

The clock test principle is based on the comparison of two independent clock sources. If the test routine detects a change in the frequency ratio between the clock sources, a fail error code is returned. The test routine uses one timer and one periodical event in the application. The periodical event could be also an interrupt from a different timer than that already involved.

The device supported by the library has many timer/counter modules. See [Core self-test library – source code version](#) for a function suitable for your device.

The block diagram for the clock test is shown in the following figure:

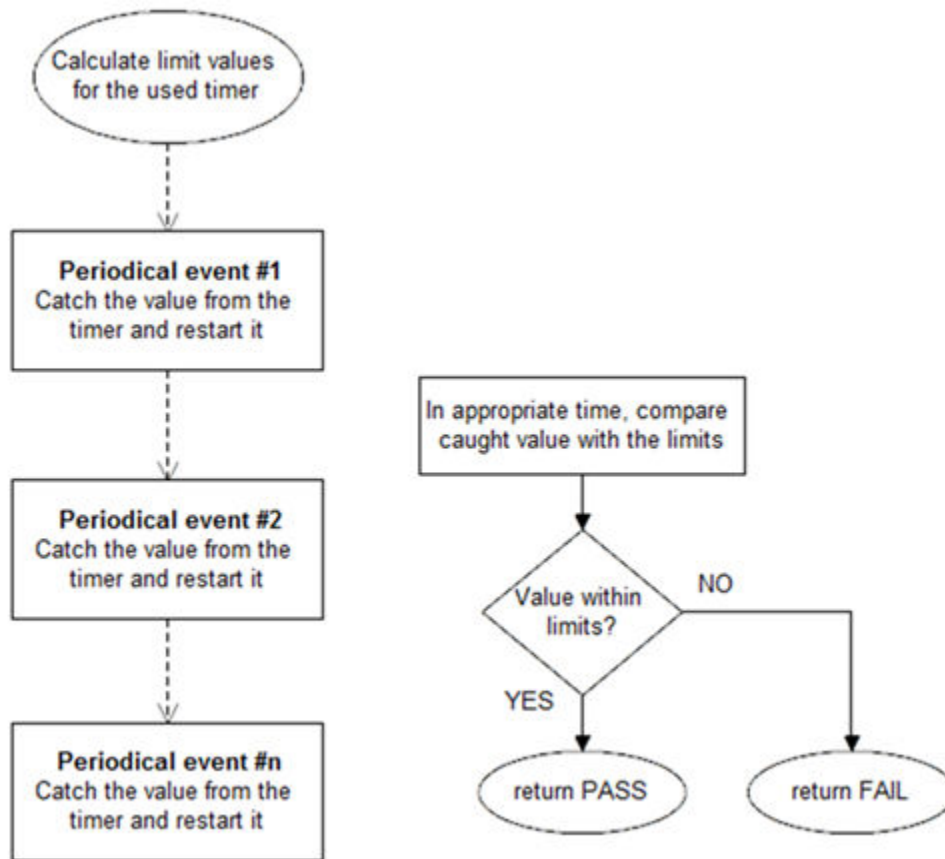


Figure 2. Block diagram for clock test

## 3.1 Clock test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to the EC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

Table 4. Clock test in compliance with IEC and UL standards

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
Clock test	3.Clock	Wrong frequency	B / R.1	Frequency monitoring

## 3.2 Clock test implementation

The test functions for the clock test are placed in the *iec60730b\_clock.c* file and written as "C" functions. The header file with the function prototypes is *iec60730b\_clock.h*. The common library header file is *iec60730b.h*.

The following functions are called to test the clock frequency:

- FS\_CLK\_Init()
- FS\_CLK\_LPTMR() / FS\_CLK\_RTC() / FS\_CLK\_GPT() / FS\_CLK\_WKT\_LPC() / FS\_CLK\_TIMER\_LPC()
- FS\_CLK\_Check()

Configure the reference timer, choose an appropriate periodical event and calculate the limit values. Declare the 32-bit global variable for storing the content of the timer counter register. The clock source of the chosen timer must differ from the clock source of the periodical event. The FS\_CLK\_Init() function is called once, normally before the while() loop. The FS\_CLK\_LPTMR() (to choose the dedicated function for your device, see [Core self-test library – source code version](#)) function is then called within a periodic event. The FS\_CLK\_Check() function for evaluation can be called at any given time. When the test is in the initialization phase, the check function returns the "in progress" value. If the captured value from the reference counter is within the preset limits, the check function returns a pass value. If not, a defined fail value is returned.

The example of the test implementation is as follows:

```
#include "iec60730b.h"

FS_RESULT st;

unsigned long clockTestContext;

#define ISR_FREQUENCY (100)

#define CLOCK_TEST_TOLERANCE (10)

#define REF_TIMER_CLOCK_FREQUENCY (32e03l)

RTC_SC = RTC_SC_RTCLKS(2)|RTC_SC_RTCPS(1);

SysTick->VAL = 0x0;

SysTick->LOAD = 100e6*0.01;

SysTick->CTRL = SysTick_CTRL_CLKSOURCE_Msk | SysTick_CTRL_ENABLE_Msk|
SysTick_CTRL_TICKINT_Msk;

SysTick->VAL = 0x0;

FS_CLK_Init(&clockTestContext);

while(1) { st = FS_CLK_Check(clockTestContext,FS_CLK_FREQ_LIMIT_LO, FS_CLK_FREQ_LIMIT_HI);
if(FS_CLK_FAIL == st) SafetyError();
}

void timer_isr(void)
{
FS_CLK_RTC((uint32_t*)RTC_BASE_PTR, &clockTestContext);
```

```
}

```

### 3.2.1 FS\_CLK\_Init()

This function initializes one instance of the clock sync test. It sets the TestContext value to the “in progress” state.

**Function prototype:**

```
void FS_CLK_Init(uint32_t *pTestContext);
```

**Function inputs:**

*\*pTestContext* - The pointer to the variable that holds the captured timer value.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

### 3.2.2 FS\_CLK\_Check()

This function handles the clock test. It evaluates the captured value stored in the testContext variable with predefined limits. Until the first execution of the respective Lsr function, the check function returns FS\_CLK\_PROGRESS.

**Function prototype:**

```
FS_RESULT FS_CLK_Check(uint32_t testContext, uint32_t limitLow, uint32_t limitHigh);
```

**Function inputs:**

*testContext* - The captured value of the timer.

*limitLow* - The low limit.

*limitHigh* - The high limit.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS* - The testContext fits into the limits.
- *FS\_FAIL\_CLK* - The testContext value does not fit into the limits.
- *FS\_CLK\_PROGRESS* - The reference counter value is not read yet.

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

### 3.2.3 FS\_CLK\_LPTMR()

This function is used only with the LPTMR module. The function reads the counter value from the timer and saves it into the TestContext variable. After that, the function starts the LPTMR again.

**Function prototype:**

```
void FS_CLK_LPTMR(uint32_t *pSafetyTmr, uint32_t *pTestContext);
```

**Function inputs:**

*\*pSafetyTmr* - The timer module address.

*\*pTestContext* - The pointer to the variable that holds the captured timer value.

Clock test

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 3.2.4 FS\_CLK\_CTIMER\_LPC()

This function is used only with the CTimer module. This function reads the counter value from the timer and saves it into the TestContext variable. After that, it starts the CTimer again.

**Function prototype:**

```
void FS_CLK_CTIMER_LPC(uint32_t *pSafetyTmr, uint32_t *pTestContext);
```

**Function inputs:**

*\*pSafetyTmr* - The timer module address.

*\*pTestContext* - The pointer to the variable that holds the captured timer value.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 3.2.5 FS\_CLK\_GPT()

This function is used only with the GPT module. This function reads the counter value from the timer and saves it into the TestContext variable. After that, it starts the GPT again.

**Function prototype:**

```
void FS_CLK_GPT(uint32_t *pSafetyTmr, uint32_t *pTestContext);
```

**Function inputs:**

*\*pSafetyTmr* - The timer module address.

*\*pTestContext* - The pointer to the variable that holds the captured timer value.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

## 3.2.6 FS\_CLK\_RTC()

This function is used only with the RTC module. This function reads the counter value from the timer and saves it into the TestContext variable. After that, it starts the RTC again.

**Function prototype:**

```
void FS_CLK_RTC(uint32_t *pSafetyTmr, uint32_t *pTestContext);
```

**Function inputs:**

*\*pSafetyTmr* - The timer module address.

*\*pTestContext* - The pointer to the variable that holds the captured timer value.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

### 3.2.7 FS\_CLK\_WKT\_LPC()

This function is used only with the WKT module. This function reads the counter value from the timer and saves it into the TestContext variable. After that, it starts the WKT again.

**Function prototype:**

```
void FS_CLK_WKT_LPC(uint32_t *pSafetyTmr, uint32_t *pTestContext, uint32_t startValue);
```

**Function inputs:**

*\*pSafetyTmr* - The timer module address.

*\*pTestContext* - The pointer to the variable that holds the captured timer value.

*startValue* - The start value to decrease the WKT counter.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

# Chapter 4

## Digital input/output test

The Digital Input/Output (DIO) test procedure performs the plausibility check of the processor's digital IO interface.

The identification of the safety error is ensured by the specific FAIL return in case of the digital IO error. Assess the return value of the test function and if it is equal to the FAIL return, the move into the safety error handling function should occur. The safety error handling function may be specific to the application and it is not a part of the library. The main purpose of this function is to put the application into a safe state.

The DIO test functions are designed to check the digital input and output functionality and short circuit conditions between the tested pin and the supply voltage, ground, or optional adjacent pin. The execution of the DIO tests must be adapted to the final application. Be careful with the hardware connections and design. Be sure about which functions can be applied to a respective pin. In most of cases, the tested (and sometimes also auxiliary) pin must be reconfigured during the application run. When testing the digital output, reserve enough time between the test arrangement and the reading of results.

### 4.1 Digital input/output test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to the IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

**Table 5. Digital input/output test in compliance with IEC and UL standards**

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
Input/Output periphery	7. Input/Output periphery (7.1 – Digital I/O)	Abnormal operation	B/R.1	Plausibility check

### 4.2 Digital input/output test implementation

The test functions for the digital IO test are placed in the *iec60730b\_dio.c* and *iec60730b\_dio\_ext.c* files. The header files with the function prototypes are *iec60730b\_dio.h* and *iec60730b\_dio\_ext.h*. The *iec60730b.h* file is a common file for all components of the library.

The digital input/output tests can be executed using the following functions properly:

- FS\_DIO\_Input()
- FS\_DIO\_Output() / FS\_DIO\_Output\_RT() / FS\_DIO\_Output\_LPC()
- FS\_DIO\_InputExt() / FS\_DIO\_InputExt\_RT() / FS\_DIO\_InputExt\_LPC()
- FS\_DIO\_ShortToSupplySet() / FS\_DIO\_ShortToSupplySet\_RT() / FS\_DIO\_ShortToSupplySet\_LPC()
- FS\_DIO\_ShortToAdjSet() / FS\_DIO\_ShortToAdjSet\_RT() / FS\_DIO\_ShortToAdjSet\_LPC()

The pointer to the *fs\_dio\_test\_t* structure type is a parameter of each function. The structure is defined in the *iec60730b\_dio.h* file.

```
typedef struct
{
    uint32_t pcr; /* Pin control register */
    uint32_t pddr; /* Port data direction register */
    uint32_t pdor; /* Port data output register */
} fs_dio_backup_t;
```



```

typedef struct
{
    uint32_t gpio;
    fs_dio_backup_t pcr;
    uint8_t pinNum;
    uint8_t pinDir;
    uint8_t pinMux;
    fs_dio_backup_t sTestedPinBackup;
} fs_dio_test_t;

```

These variables must be initialized before calling a test function. The following is an example of initialization:

```

fs_dio_test_t dio_safety_test_item_0 =
{
    .gpio = FS_DIO_PORTE,
    .pinNum = 24,
    .pinDir = PIN_DIRECTION_IN,
    .pinMux = PIN_MUX_GPIO,
};
fs_dio_test_t dio_safety_test_item_1 =
{
    .gpio = FS_DIO_PORTA,
    .pinNum = 2,
    .pinDir = PIN_DIRECTION_OUT,
    .pinMux = PIN_MUX_GPIO,
};
fs_dio_test_t *dio_safety_test_items[] = { &dio_safety_test_item_0, &dio_safety_test_item_1, 0 };

if (dio_safety_test_item_0 .gpio == FS_DIO_PORTE)
    dio_safety_test_item_0 .pcr = FS_DIO_PORTE_PCR;

if (dio_safety_test_item_1 .gpio == FS_DIO_PORTA)
    dio_safety_test_item_1 .pcr = FS_DIO_PORTA_PCR;

```

## 4.2.1 FS\_DIO\_Input()

This function executes the digital input test. The test tests one digital pin. The pin is tested according to the block diagram in the following figure:

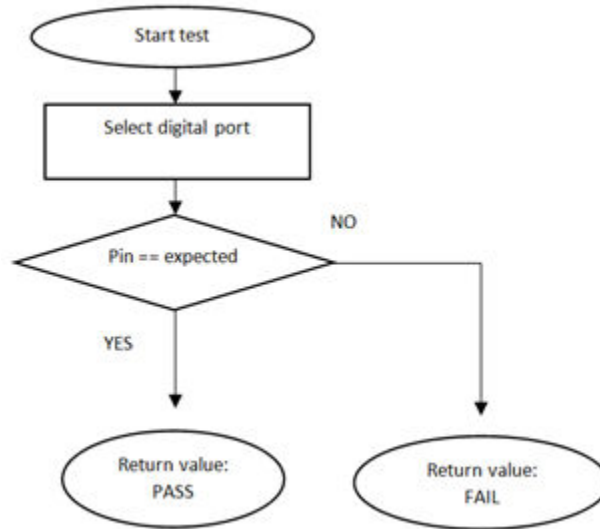


Figure 3. Block diagram for digital input test

**Function prototype:**

*FS\_RESULT FS\_DIO\_Input(fs\_dio\_test\_t \*pTestedPin, bool\_t expectedValue);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*expectedValue* - The expected input value. Adjust this parameter correctly.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

*fs\_dio\_input\_test\_result = FS\_DIO\_Input(&dio\_safety\_test\_items[0], DIO\_EXPECTED\_VALUE);*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configured as a GPIO with input direction.

## 4.2.2 FS\_DIO\_InputExt()

This is a modified version of the previously mentioned digital input test. It cannot be used with MKE0x devices. This version is a get function for the "short-to" tests. The function is applied to the pin that is already configured as a GPIO input and you know what logical level is expected at the time of the test. The logical level can result from the actual configuration in the application or it can be initialized for the test (if possible). The block diagram of the *FS\_DIO\_InputExt()* function is shown in the following figure. Two function input parameters are related to an adjacent pin. For a simple input test functionality, these parameters are not important. Enter the same inputs as for the tested pin (recommended). See the example code.

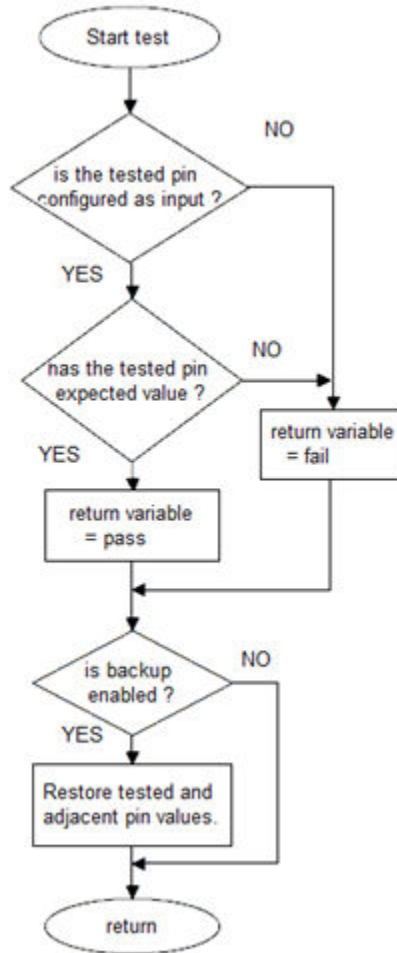


Figure 4. Extended digital input test

**Function prototype:**

```
FS_RESULT FS_DIO_InputExt(fs_dio_test_t *pTestedPin, fs_dio_test_t *pAdjPin, bool_t testedPinValue, bool_t backupEnable);
```

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*\*pAdjPin* - The pointer to the adjacent pin struct.

*testedPinValue* - The expected value of the tested pin (logical 0 or logical 1). Adjust this parameter correctly.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

```
fs_dio_input_test_result = FS_DIO_InputExt(&dio_safety_test_item_0, &dio_safety_test_item_0, DIO_EXPECTED_VALUE, BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The function cannot be used with MKE0x devices. The tested pin must be configured as a GPIO input before calling the function. Even if no adjacent pin is involved in the test, specify the AdjacentPin parameter. It is recommended to enter the same input as for the TestedPin.

### 4.2.3 FS\_DIO\_InputExt\_RT()

This is a modified version of the previously mentioned digital input test. Use this version as a get function for the "short-to" tests. Apply the function to the pin that is already configured as a GPIO input and you know what logical level is expected at the time of the test. The logical level results from the actual configuration in the application or it is initialized for the test (if possible). The block diagram of the *FS\_DIO\_InputExt\_RT()* function is shown in the following figure. Two function input parameters are related to an adjacent pin. For simple input test functionality, these parameters are not important. Enter the same inputs as for the tested pin (recommended). See the example code.

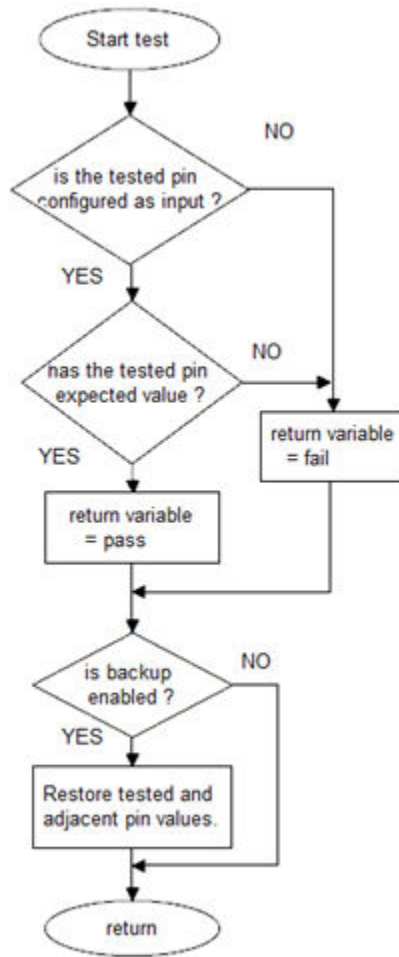


Figure 5. Extended digital input test for RT

**Function prototype:**

*FS\_RESULT FS\_DIO\_InputExt\_RT(fs\_dio\_test\_rt\_t \*pTestedPin, fs\_dio\_test\_rt\_t \*pAdjPin, bool\_t testedPinValue, bool\_t backupEnable);*

**Function inputs:**

- \*pTestedPin - The pointer to the tested pin struct.
- \*pAdjPin - The pointer to the adjacent pin struct.

*testedPinValue* - The expected value of the tested pin (logical 0 or logical 1). Adjust this parameter correctly.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

`typedef uint32_t FS_RESULT;`

- `FS_PASS`
- `FS_FAIL_DIO`

**Example of function call:**

```
fs_dio_input_test_result = FS_DIO_InputExt_RT(&dio_safety_test_item_0, &dio_safety_test_item_0, DIO_EXPECTED_VALUE,
BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The function can be used only for the i.MXRT devices. Configure the tested pin as a GPIO input before calling the function. Even if no adjacent pins are involved in the test, specify the `AdjacentPin` parameter. It is recommended is enter the same input as for `TestedPin`.

## 4.2.4 FS\_DIO\_InputExt\_LPC()

This is a modified version of the previously mentioned digital input test. This version is used as a get function for the "short-to" tests. Apply the function to the pin that is already configured as a GPIO input and you know what logical level is expected at the time of the test. The logical level can either result from the actual configuration in the application or it can be initialized for the test (if possible). The block diagram of the `FS_DIO_InputExt_LPC()` function is shown in the following figure. Two function input parameters are related to an adjacent pin. For simple input test functionality, these parameters are not important. Enter the same inputs as for the tested pin (recommended). See the example code.

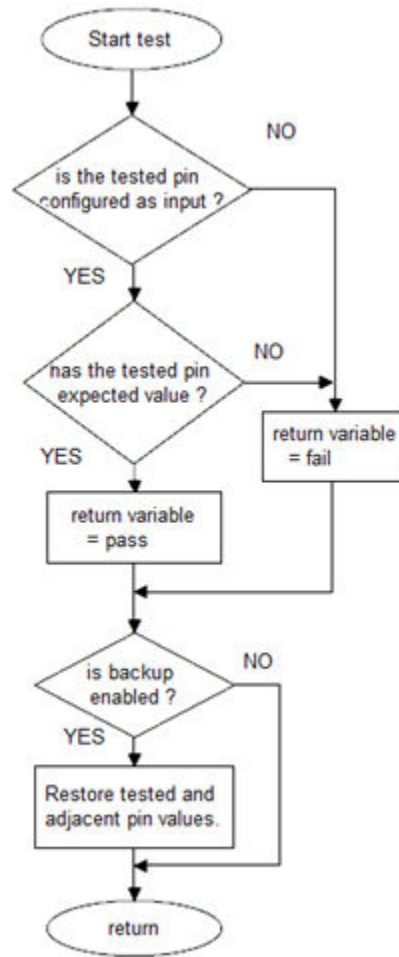


Figure 6. Extended digital input test for LPC devices

**Function prototype:**

*FS\_RESULT FS\_DIO\_InputExt\_LPC(fs\_dio\_test\_lpc\_t \*pTestedPin, fs\_dio\_test\_lpc\_t \*pAdjPin, bool\_t testedPinValue, bool\_t backupEnable);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*\*pAdjPin* - The pointer to the adjacent pin struct.

*testedPinValue* - The expected value of the tested pin (logical 0 or logical 1). Adjust this parameter correctly.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

*fs\_dio\_input\_test\_result = FS\_DIO\_InputExt\_LPC(&dio\_safety\_test\_item\_0, &dio\_safety\_test\_item\_0, DIO\_EXPECTED\_VALUE, BACKUP\_ENABLE);*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

Configure the tested pin as a GPIO input before the function call. Even if no adjacent pins are involved in the test, specify the AdjacentPin parameter. It is recommended to enter the same input as for the TestedPin.

## 4.2.5 FS\_DIO\_Output()

The digital output test tests the digital output functionality of the pin. The principle of the test is to set up and read both logical values on the tested pin. Enter a suitable delay parameter. It must ensure a time interval that is long enough for the device to reach the desired logical value on the pin. A very low delay parameter causes the fail return value of the function.

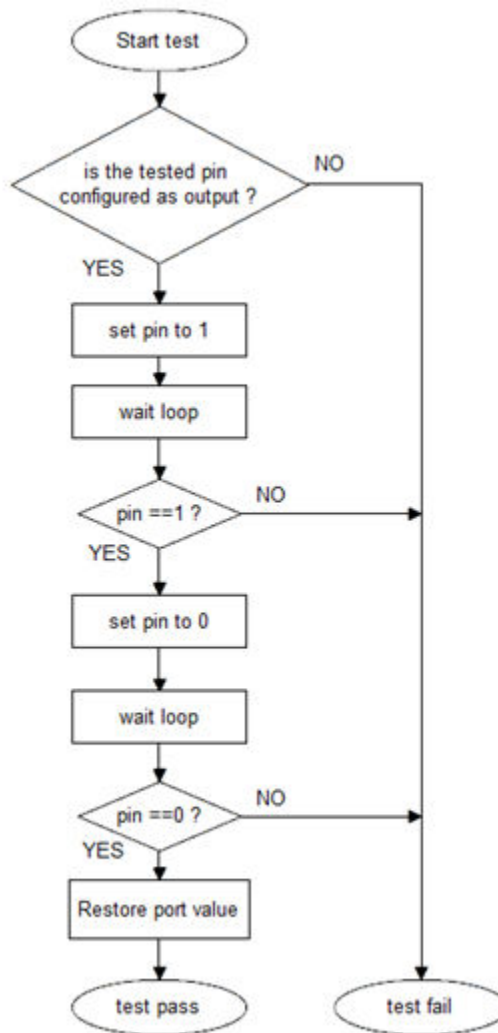


Figure 7. Block diagram for digital output test

**Function prototype:**

*FS\_RESULT FS\_DIO\_Output(fs\_dio\_test\_t \*pTestedPin, uint32\_t delay);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*delay* - The delay needed to recognize the value change on the tested pin.

**Function output:**

Digital input/output test

```
typedef uint32_t FS_RESULT;
```

- `FS_PASS`
- `FS_FAIL_DIO`

**Example of function call:**

```
fs_dio_output_test_result = FS_DIO_Output(&dio_safety_test_items[1], DIO_WAIT_CYCLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configured as the digital output. Define an appropriate delay for proper functionality.

## 4.2.6 FS\_DIO\_Output\_RT()

This test tests the digital output functionality of the pin. The principle of this test is to set up and read both logical values on the tested pin. Enter a suitable delay parameter. It must ensure a time interval that is long enough for the device to reach the desired logical value on the pin. A very low delay parameter causes the fail return value of the function.

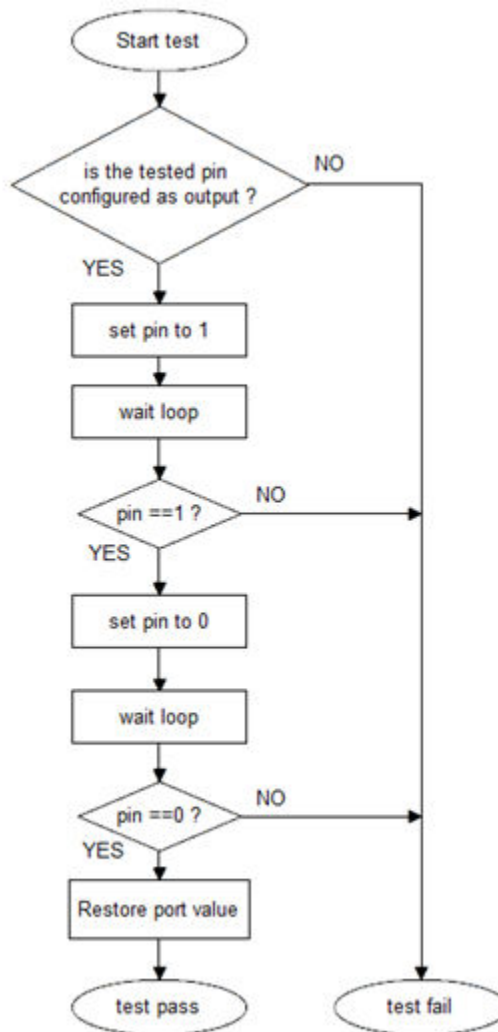


Figure 8. Block diagram for digital output test



**Function prototype:**

```
FS_RESULT FS_DIO_Output_RT(fs_dio_test_rt_t *pTestedPin, uint32_t delay);
```

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*delay* - The delay needed to recognize the value change on the tested pin.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

```
fs_dio_output_test_result = FS_DIO_Output_RT(&dio_safety_test_items[1], DIO_WAIT_CYCLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configured as a digital output. Define an appropriate delay for proper functionality.

## 4.2.7 FS\_DIO\_Output\_LPC()

This test tests the digital output functionality of the pin. The principle of the test is to set up and read both logical values on the tested pin. A suitable delay parameter must be entered. It must ensure a time interval that is long enough for the device to reach the desired logical value on the pin. A very low delay parameter causes the fail return value of the function.

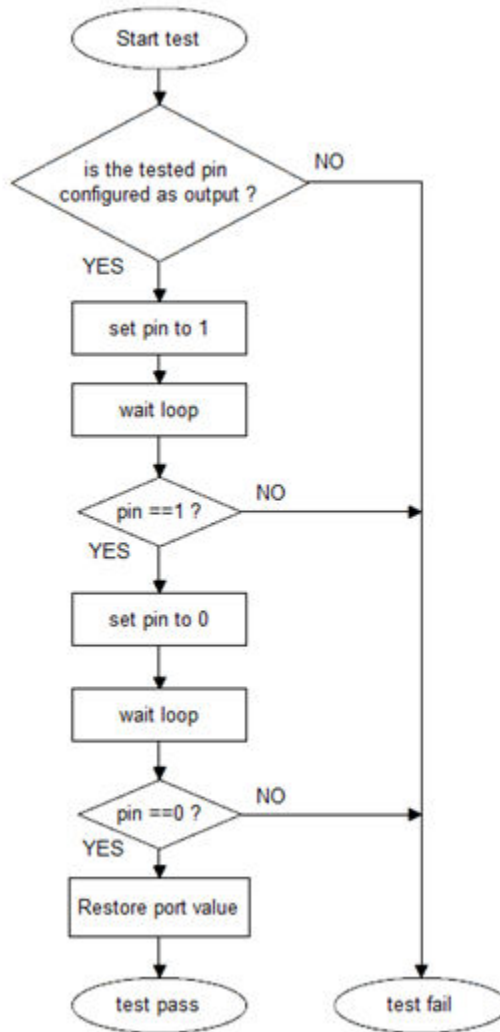


Figure 9. Block diagram for digital output test

**Function prototype:**

*FS\_RESULT FS\_DIO\_Output\_LPC(fs\_dio\_test\_ipc\_t \*pTestedPin, uint32\_t delay);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*delay* - The delay needed to recognize the value change on the tested pin.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

*fs\_dio\_output\_test\_result = FS\_DIO\_Output\_LPC(&dio\_safety\_test\_items[1], DIO\_WAIT\_CYCLE);*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configured as a digital output. Define an appropriate delay for proper functionality.

## 4.2.8 FS\_DIO\_ShortToAdjSet()

This function ensures the required conditions for the short-to-adjacent pin test. The purpose of this function is to configure the tested pin and the adjacent pin properly. The adjacent pin is an optional pin that can be theoretically shorted with the tested pin. The function block diagram is shown in the following figure. Similarly to the short-to-supply test, this test requires the use of two functions. The second (get) function evaluates the test result. The *FS\_DIO\_InputExt()* function is described in the respective section. Specify the tested pin and the adjacent pin for the input test function.

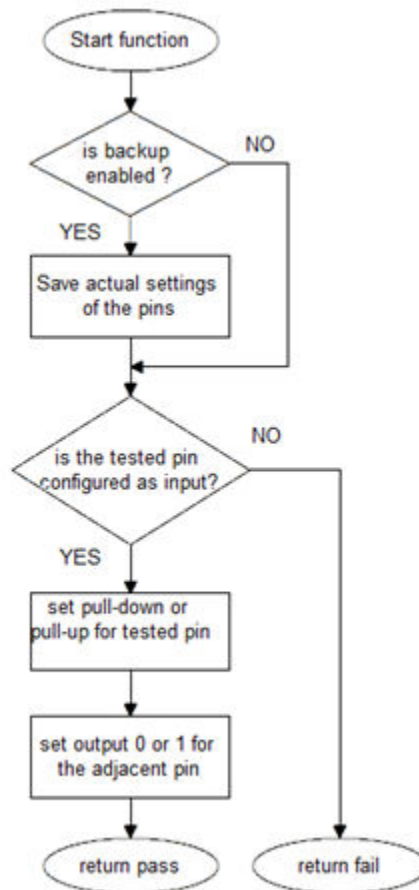


Figure 10. Block diagram of FS\_DIO\_ShortToAdjSet() function

### Function prototype:

```
FS_RESULT FS_DIO_ShortToAdjSet(fs_dio_test_t *pTestedPin, fs_dio_test_t *pAdjPin, bool_t testedPinValue, bool_t backupEnable);
```

### Function inputs:

*\*pTestedPin* - The pointer to the tested pin struct.

*\*pAdjPin* - The pointer to the adjacent pin struct.

*testedPinValue* - The value to be set on the tested pin.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

### Function output:

```
typedef uint32_t FS_RESULT;
```

Digital input/output test

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is the code example of the short-to-adjacent pin test.

```
#define BACKUP_ENABLE 1
#define LOGICAL_ONE 1
#define LOGICAL_ZERO 0

dio_short_to_adj_test_result = FS_DIO_ShortToAdjSet(&dio_safety_test_items[0], &dio_safety_test_items[1],
LOGICAL_ONE, BACKUP_ENABLE);

dio_short_to_adj_test_result =FS_DIO_InputExt(&dio_safety_test_items[0], &dio_safety_test_items[1],
LOGICAL_ONE, BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The function cannot be used with MKE0x devices. The tested must be configured as GPIO input and adjacent pins must be configured as a GPIO output before calling the function. If the backup functionality is enabled, the function sets directions for both pins. If not, configure the directions (the tested pin as the input, the adjacent pin as the output). After the end of the function, the application cannot manipulate neither the tested nor the adjacent pins until the *FS\_DIO\_InputExt()* function is called for these pins.

## 4.2.9 FS\_DIO\_ShortToAdjSet\_RT()

This function ensures the required conditions for the short-to-adjacent pin test. The purpose of this function is to configure the tested pin and the adjacent pin properly. The adjacent pin is an optional pin that can be theoretically shorted with the tested pin. The function block diagram is shown in the following figure. Similarly to the short-to-supply test, this test requires the use of two functions. The second (get) function evaluates the test result. The *FS\_DIO\_InputExt\_RT()* function is described in the respective chapter. Specify the tested pin and the adjacent pin for the input test function.

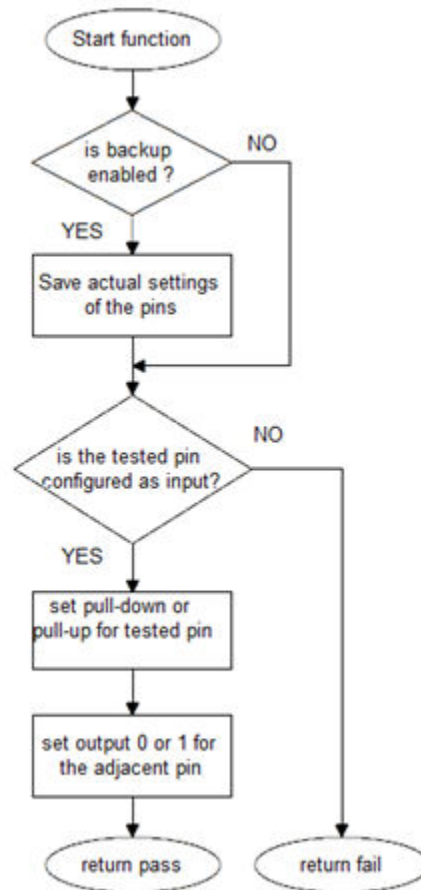


Figure 11. Block diagram of FS\_DIO\_ShortToAdjSet\_RT() function

**Function prototype:**

*FS\_RESULT FS\_DIO\_ShortToAdjSet\_RT(fs\_dio\_test\_rt\_t \*pTestedPin, fs\_dio\_test\_rt\_t \*pAdjPin, bool\_t testedPinValue, bool\_t backupEnable);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*\*pAdjPin* - The pointer to the adjacent pin struct.

*testedPinValue* - The value that is set on the tested pin.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is a code example of the short-to-adjacent pin test.

```

#define BACKUP_ENABLE 1
#define LOGICAL_ONE 1
  
```

```
#define LOGICAL_ZERO 0

dio_short_to_adj_test_result = FS_DIO_ShortToAdjSet_RT(&dio_safety_test_items[0],
&dio_safety_test_items[1], LOGICAL_ONE, BACKUP_ENABLE);

dio_short_to_adj_test_result =FS_DIO_InputExt_RT(&dio_safety_test_items[0], &dio_safety_test_items[1],
LOGICAL_ONE, BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configure as GPIO input and the adjacent pin must be configured as a GPIO output before calling the function. If the backup functionality is enabled, the function sets the directions for both pins. If not, configure the directions (tested pin as input, adjacent pin as output). After the end of the function, the application cannot manipulate neither the tested pin nor the adjacent pin until the *FS\_DIO\_InputExt\_RT()* function for these pins is called.

### 4.2.9.1 FS\_DIO\_ShortToAdjSet\_LPC()

This function ensures the required conditions for the short-to-adjacent pin test. The purpose of this function is to configure the tested pin and the adjacent pin properly. The adjacent pin is an optional pin that can be theoretically shorted with the tested pin. The function block diagram is shown in the following figure. Similarly to the short-to-supply test, this test requires the use of two functions. The second (get) function evaluates the test result. The *FS\_DIO\_InputExt\_LPC()* function is described in the respective section. Specify the tested pin and the adjacent pin for the input test function.

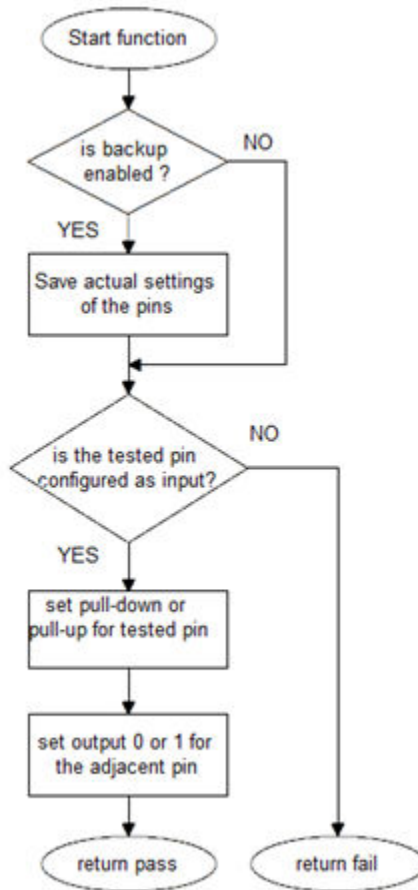


Figure 12. Block diagram of FS\_DIO\_ShortToAdjSet\_LPC() function

**Function prototype:**

```
FS_RESULT FS_DIO_ShortToAdjSet_LPC(fs_dio_test_lpc_t *pTestedPin, fs_dio_test_lpc_t *pAdjPin, bool_t testedPinValue,
bool_t backupEnable);
```

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*\*pAdjPin* - The pointer to the adjacent pin struct.

*testedPinValue* - The value that is set on the tested pin.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is a code example of the short-to-adjacent pin test.

```
#define BACKUP_ENABLE 1
#define LOGICAL_ONE 1
#define LOGICAL_ZERO 0

dio_short_to_adj_test_result = FS_DIO_ShortToAdjSet_LPC(&dio_safety_test_items[0],
&dio_safety_test_items[1], LOGICAL_ONE, BACKUP_ENABLE);

dio_short_to_adj_test_result =FS_DIO_InputExt_LPC(&dio_safety_test_items[0], &dio_safety_test_items[1],
LOGICAL_ONE, BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested must be configured as GPIO input and adjacent pins must be configured as a GPIO output before calling the function. If the backup functionality is enabled, the function sets the directions for both pins. If not, configure the directions (tested pin as input, adjacent pin as output). After the end of the function, the application cannot manipulate neither the tested nor the adjacent pins, until the *FS\_DIO\_InputExt\_LPC()* function for these pins is called.

## 4.2.10 FS\_DIO\_ShortToAdjSet\_LPC()

This function ensures the required conditions for the short-to-adjacent pin test. The purpose of this function is to configure the tested pin and the adjacent pin properly. The adjacent pin is an optional pin that can be theoretically shorted with the tested pin. The function block diagram is shown in the following figure. Similarly to the short-to-supply test, this test requires the use of two functions. The second (get) function evaluates the test result. The *FS\_DIO\_InputExt\_LPC()* function is described in the respective section. Specify the tested pin and the adjacent pin for the input test function.

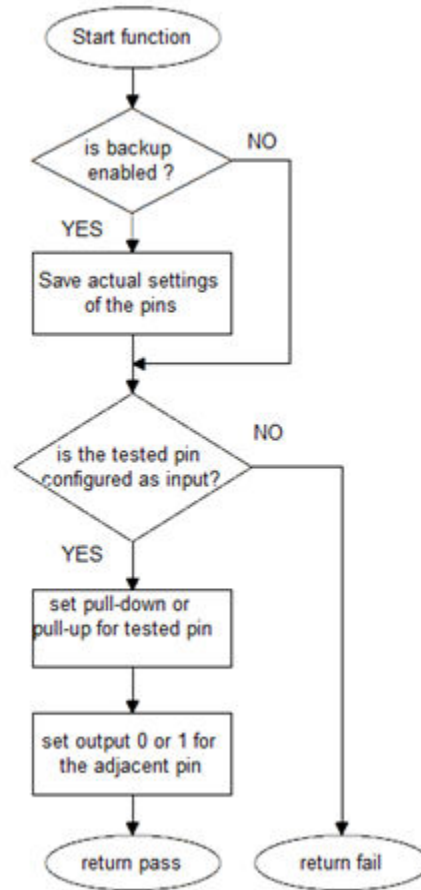


Figure 13. Block diagram of FS\_DIO\_ShortToAdjSet\_LPC() function

**Function prototype:**

*FS\_RESULT FS\_DIO\_ShortToAdjSet\_LPC(fs\_dio\_test\_lpc\_t \*pTestedPin, fs\_dio\_test\_lpc\_t \*pAdjPin, bool\_t testedPinValue, bool\_t backupEnable);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*\*pAdjPin* - The pointer to the adjacent pin struct.

*testedPinValue* - The value that is set on the tested pin.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is a code example of the short-to-adjacent pin test.

```

#define BACKUP_ENABLE 1
#define LOGICAL_ONE 1
    
```



```

#define LOGICAL_ZERO 0

dio_short_to_adj_test_result = FS_DIO_ShortToAdjSet_LPC(&dio_safety_test_items[0],
&dio_safety_test_items[1], LOGICAL_ONE, BACKUP_ENABLE);

dio_short_to_adj_test_result =FS_DIO_InputExt_LPC(&dio_safety_test_items[0], &dio_safety_test_items[1],
LOGICAL_ONE, BACKUP_ENABLE);

```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested must be configured as GPIO input and adjacent pins must be configured as a GPIO output before calling the function. If the backup functionality is enabled, the function sets the directions for both pins. If not, configure the directions (tested pin as input, adjacent pin as output). After the end of the function, the application cannot manipulate neither the tested nor the adjacent pins, until the *FS\_DIO\_InputExt\_LPC()* function for these pins is called.

## 4.2.11 FS\_DIO\_ShortToSupplySet()

This function creates the first part of the short-to-supply test. It can be used to test the short circuit between the tested pin and the hardware supply voltage (Vcc, Vdd) or between the tested pin and the hardware ground (GND). Its block diagram is shown in the following figure. The second part of the test (result evaluation) is ensured by the *FS\_DIO\_InputExt()* function that is described in the respective section. The main purpose of the *FS\_DIO\_InputExt()* function is to set the pull-up (or pull-down) resistor connection on the tested pin. It also ensures whether the pin is correctly configured and backs up its settings (if needed).

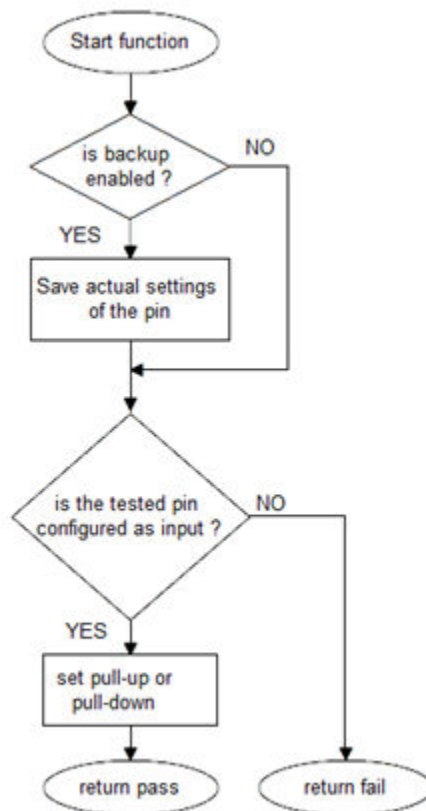


Figure 14. Block diagram of FS\_DIO\_ShortToSupplySet function

Digital input/output test

**Function prototype:**

```
FS_RESULT FS_DIO_ShortToSupplySet(fs_dio_test_t *pTestedPin, bool_t shortToVoltage, bool_t backupEnable);
```

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*shortToVoltage* - Specifies whether the pin is tested for the short against GND or Vdd. For GND, enter 1. For VDD, enter 0 or non-zero.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is a code example of the test for both the short-to-GND and short-to-VDD cases. Note that the implementation difference is only in one parameter. If the short to GND is tested, the parameter must have non-zero value and vice versa.

```
#define DIO_SHORT_TO_GND_TEST 1
#define DIO_SHORT_TO_VDD_TEST 0

dio_short_to_vcc_test_result = FS_DIO_ShortToSupplySet(&dio_safety_test_items[0],
DIO_SHORT_TO_GND_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_InputExt(&dio_safety_test_items[0], &dio_safety_test_items[0],
DIO_SHORT_TO_GND_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_ShortToSupplySet(&dio_safety_test_items[0],
DIO_SHORT_TO_VDD_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_InputExt(&dio_safety_test_items[0], &dio_safety_test_items[0],
DIO_SHORT_TO_VDD_TEST, BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The function cannot be used with MKE0x devices. The tested pin must be configured as a GPIO input before calling the function. If the backup functionality is enabled, the function sets the input direction for the tested pin. If not, configure the input direction. After the end of the function, the application cannot manipulate the tested pin until the *FS\_DIO\_InputExt()* function for the tested pin is called.

## 4.2.12 FS\_DIO\_ShortToSupplySet\_RT()

This function creates the first part of the short-to-supply test. It can be used to test the short circuit between the tested pin and the hardware supply voltage (VCC, VDD) or between the tested pin and the hardware ground (GND). Its block diagram is shown in the following figure. The second part of the test (result evaluation) is ensured by the *FS\_DIO\_InputExt\_RT()* function described in the respective section. The main purpose of the *FS\_DIO\_InputExt\_RT()* function is to set the pull-up or pull-down resistor connections on the tested pin. It also ensures whether the pin is correctly configured and makes a backup of its settings (if needed).

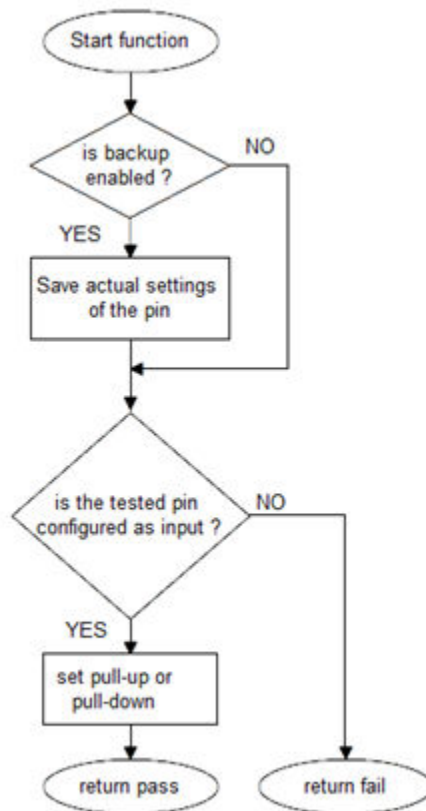


Figure 15. Block diagram of FS\_DIO\_ShortToSupplySet\_RT function

**Function prototype:**

*FS\_RESULT FS\_DIO\_ShortToSupplySet\_RT(fs\_dio\_test\_rt\_t \*pTestedPin, bool\_t shortToVoltage, bool\_t backupEnable);*

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*shortToVoltage* - Specifies whether the pin is tested for a short against GND or VDD. For GND, enter 1. For VDD, enter 0 or non-zero.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is a code example of the test for both the short-to-GND and short-to-VDD cases. Note that the implementation difference is only in one parameter. If the short to the GND is tested, the parameter must have a non-zero value (vice versa).

```

#define DIO_SHORT_TO_GND_TEST 1
#define DIO_SHORT_TO_VDD_TEST 0

dio_short_to_vcc_test_result = FS_DIO_ShortToSupplySet_RT(&dio_safety_test_items[0],
DIO_SHORT_TO_GND_TEST, BACKUP_ENABLE);
  
```

```

dio_short_to_vcc_test_result = FS_DIO_InputExt_RT(&dio_safety_test_items[0], &dio_safety_test_items[0],
DIO_SHORT_TO_GND_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_ShortToSupplySet_RT(&dio_safety_test_items[0],
DIO_SHORT_TO_VDD_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_InputExt_RT(&dio_safety_test_items[0], &dio_safety_test_items[0],
DIO_SHORT_TO_VDD_TEST, BACKUP_ENABLE);
    
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configured as the GPIO input before calling the function. If the backup functionality is enabled, the function sets the input direction for the tested pin. If not, configure the input direction. After the end of the function, the application cannot manipulate the tested pin until the *FS\_DIO\_InputExt\_RT()* function is called for the tested pin.

### 4.2.13 FS\_DIO\_ShortToSupplySet\_LPC()

This function creates the first part of the short-to-supply test. It can be used to test the short circuit between the tested pin and the hardware supply voltage (Vcc, Vdd) or between the tested pin and the hardware ground (GND). Its block diagram is shown in the following figure. The second part of the test (result evaluation) is ensured by the *FS\_DIO\_InputExt\_LPC()* function described in the respective section. The main purpose of the *FS\_DIO\_InputExt\_LPC()* function is to set the pull-up or pull-down resistor connections on the tested pin. It also tests whether the pin is correctly configured and makes a backup of its settings (if needed).

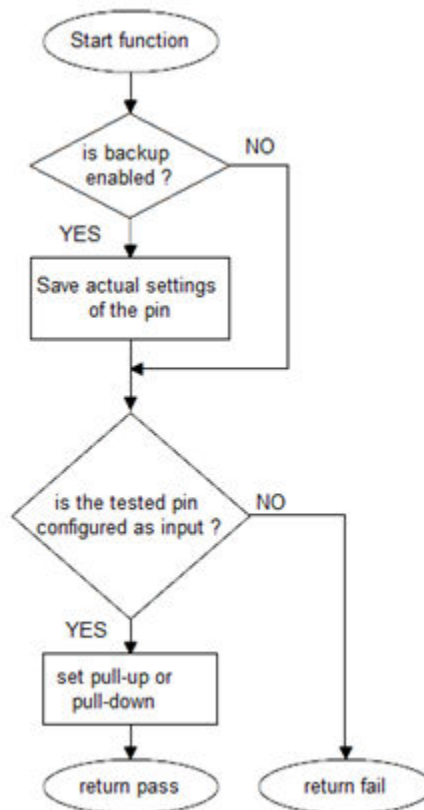


Figure 16. Block diagram of FS\_DIO\_ShortToSupplySet\_LPC function

**Function prototype:**

```
FS_RESULT FS_DIO_ShortToSupplySet_LPC(fs_dio_test_lpc_t *pTestedPin, bool_t shortToVoltage, bool_t backupEnable);
```

**Function inputs:**

*\*pTestedPin* - The pointer to the tested pin struct.

*shortToVoltage* - Specifies whether the pin is tested for short against GND or VDD. For GND, enter 1. For VDD - enter 0 or non-zero.

*backupEnable* - The flag. If it is non-zero, the backup functionality is enable/active.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_DIO*

**Example of function call:**

The following is a code example of the test for both the short-to-GND and short-to-VDD cases. Note that the implementation difference is only in one parameter. If the short to GND is tested, the parameter must have non-zero value (and vice versa).

```
#define DIO_SHORT_TO_GND_TEST 1
#define DIO_SHORT_TO_VDD_TEST 0

dio_short_to_vcc_test_result = FS_DIO_ShortToSupplySet_LPC(&dio_safety_test_items[0],
DIO_SHORT_TO_GND_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_InputExt_LPC(&dio_safety_test_items[0], &dio_safety_test_items[0],
DIO_SHORT_TO_GND_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_ShortToSupplySet_LPC(&dio_safety_test_items[0],
DIO_SHORT_TO_VDD_TEST, BACKUP_ENABLE);

dio_short_to_vcc_test_result = FS_DIO_InputExt_LPC(&dio_safety_test_items[0], &dio_safety_test_items[0],
DIO_SHORT_TO_VDD_TEST, BACKUP_ENABLE);
```

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The tested pin must be configured as a GPIO input before calling the function. If the backup functionality is enabled, the function sets the input direction for the tested pin. If not, configure the input direction. After the end of the function, the application cannot manipulate the tested pin until the *FS\_DIO\_InputExt\_LPC()* function for the tested pin is called.

# Chapter 5

## Invariable memory test

The invariable memory on the CM33-based MCUs is the on-chip flash. The principle of the invariable memory test is to check whether there is a change in the memory content during the application run. Several checksum methods can be used for this purpose. The checksum is an algorithm that calculates a signature of the data placed in the tested memory. The signature of this memory block is then periodically calculated and compared with the original signature.

The signature of the assigned memory is calculated in the linking phase of an application. The signature must be saved into the invariable memory, but in a different area than that the checksum is calculated for. In runtime and after the reset, the same algorithm must be implemented in the application to calculate the checksum. The results are compared and if they are not equal, a safety error state occurs.

The algorithm that calculates the checksum parameter (signature) by the IAR IDE linker must be the same as that used in runtime (16-bit CRC polynomial (0x1021) for SW16 and HW16 or 0x04C11DB7 for HW32 and SW32) to generate a CRC code for error detection. The same algorithm is implemented in the hardware CRC module.

If the hardware CRC module cannot be used for the invariable memory test, there is a possibility to use the software version of test. It has same functionality and does not require hardware support, but it is much slower.

### 5.1 Invariable memory test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to the IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

**Table 6. Invariable memory test in compliance with IEC and UL standards**

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
Invariable memory	4.1 – Invariable memory	All single bit faults	B/R.1	Periodic modified checksum

### 5.2 Invariable memory test implementation

The test functions for the flash memory are placed in the *iec60730b\_cm33\_flash.S* file. The header file with definitions and function prototypes is *iec60730b\_cm33\_flash.h*. The *iec60730b.h* and *asm\_mac\_common.h* files must be placed in the application as well. The following functions are defined in the *iec60730b\_cm33\_flash.S* file:

- FS\_CM33\_FLASH\_HW16()
- FS\_CM33\_FLASH\_HW32()
- FS\_CM33\_FLASH\_SW16()
- FS\_CM33\_FLASH\_SW32()

#### 5.2.1 Computing of CRC value in linking phase of application

The checksum of a memory block must be calculated before it is written into the flash memory. The checksum calculation is best done with a linker. However, this is not possible in all compilers. The following example is valid only for the IAR IDE. For further details, refer to the IAR documentation. For using the external tool in the Keil-uVision IDE, see Calculating Post-Build CRC in Arm® Keil® (document [AN12520](#)).

The result of the CRC calculation must be stored in the flash memory. It must not be stored in the area where the checksum occurs. A good method is to define a small block in the flash (ROM) memory, where the result of the checksum is stored. To do this, modify the linker configuration file. The path to the linker configuration file can be found in "Project > Options > Linker > Config". The file name extension is *\*.icf*. The "CHECKSUM" block with the ".checksum" section is defined in this example.

```

define symbol __FlashCRC_start__ = 0x6FF0;
define symbol __FlashCRC_end__ = 0x6FFF;
define region CRC_region = mem:[from __FlashCRC_start__ to __FlashCRC_end__];
define block CHECKSUM { section .checksum };
place in CRC_region { block CHECKSUM };

```

The input parameters for the CRC calculation must be set up in the linker option tabs "Project > Options > Linker". There are two options to set up the calculation parameters. The first option is used to calculate the checksum for one block of memory in your application. The parameters are filled in the "Checksum" subtab. In this example, the start and end addresses are 0x510 and 0x3000. The unused memory is filled with 0xFF. The checksum is stored as 16 bits. The checksum algorithm is CRC16 with the standard 0x1021 polynomial. The initial seed is zero. The block size for the particular calculation is 8 bits. The variable for the result is `__checksum`.

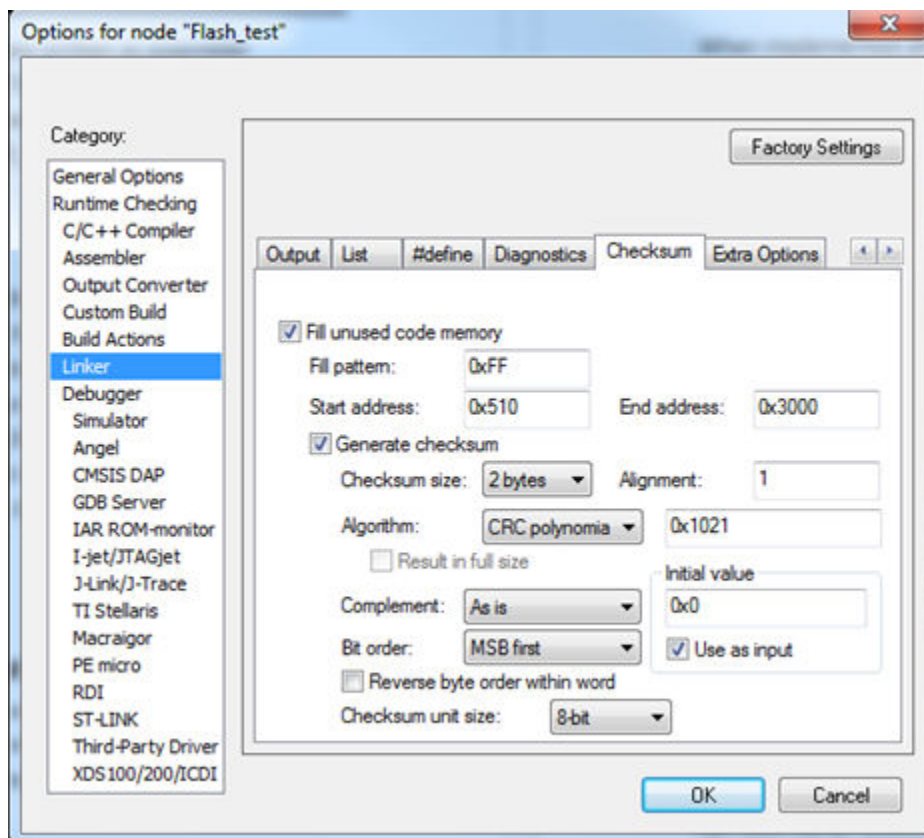


Figure 17. Checksum settings for linker

The constant variable name (`__checksum`) must be written into "Project > Options > Linker > Input > Keep symbols".

The following lines must be placed into the source code to have the `__checksum` variable available in the application:

```

#pragma section = ".checksum"
#pragma location = ".checksum"
extern unsigned short const __checksum;

```

## Invariable memory test

If you need a CRC calculation for more memory blocks, use the following approach. There must be enough space in the block defined in the linker configuration file. For this example, the parameters for the calculations are the same as in the previous example and the addresses of blocks are 0x510 – 0x610, 0x620 – 0x720, and 0x730 – 0x830. The variables are `__checksum_first`, `__checksum_second`, and `__checksum_third`. In this case, the linker command line directives are used (Project > Options > Linker > Extra Options). Allow the use of command-line options and enter the following lines there. Note that the options in the "Checksum" subtab must be unchecked.

```
—fill 0xFF;0x510-0x610  
—checksum __checksum_first:2,crc16,0x0;0x510-0x610  
—place_holder __checksum_first,2,.checksum,4  
  
—fill 0xFF;0x620-0x720  
—checksum __checksum_second:2,crc16,0x0;0x620-0x720  
—place_holder __checksum_second,2,.checksum,4  
  
—fill 0xFF;0x730-0x830  
—checksum __checksum_third:2,crc16,0x0;0x730-0x830  
—place_holder __checksum_third,2,.checksum,4
```

Project > Options > Linker > Input

Write:

```
__checksum_first  
__checksum_second  
__checksum_third
```

to the "Keep symbols" block.

Add the following lines into the source code, such that the `__checksum_first`, `__checksum_second`, and `__checksum_third` variables are available in the application.

```
#pragma section = ".checksum"  
#pragma location = ".checksum"  
extern unsigned short const __checksum_first;  
extern unsigned short const __checksum_second;  
extern unsigned short const __checksum_third;
```

## 5.2.2 Test performed once after MCU reset

When implemented after the reset or when there is no restriction to the execution time, the function call can be as follows:

```
#include "iec60730b.h"  
#pragma section = ".checksum"  
#pragma location = ".checksum"  
extern unsigned short const __checksum;
```



```

if((uint16_t)__checksum != FS_CM33_FLASH_HW166(start_address, size, CRC_BASE, start_seed))
SafetyError();

```

Where:

*\_\_checksum* - The constant variable with the CRC value computed in the linking phase of the application.

*start\_address* - The initial address of the memory block to be tested.

*size* - The size of the memory block to be tested (first address – end address + 1).

*CRC\_BASE* - The base address of the CRC hardware module.

*start\_seed* - The start condition seed. It shall be zero for the algorithm used.

## 5.2.3 Runtime test

In application runtime with limited time for execution, the CRC is computed in a sequence. It means that the input parameters have different meanings in comparison with calling after reset. The implementation is as follows:

```

#include "iec60730b.h"
#pragma section = ".checksum"
#pragma location = ".checksum"
extern unsigned short const __checksum;

flash_crc.part_crc = FS_CM33_FLASH_HW16(flash_crc.actual_address, flash_crc.block_size, CRC_BASE,
flash_crc.part_crc);

if(FS_FLASH_FAIL == Flash_test_handling(__checksum, &flash_crc))
SafetyError();

```

Where:

*\_\_checksum* - The constant variable with the CRC value computed in the linking phase of the application.

*flash\_crc.part\_crc* - The particular CRC result and seed parameter for the next iteration.

*flash\_crc.actual\_address* - The actual address of the memory block to be tested.

*CRC\_BASE* - The base address of the CRC module.

*flash\_crc.block\_size* - The size of the memory block to be tested.

Carry out the handling of the function. When the checksum of a block is calculated in more iterations, the result from the first iteration (function call) is the seed value for the next function call. After the last part of memory is processed with the test function, the result is the final checksum of the whole tested memory block.

## 5.2.4 FS\_CM33\_FLASH\_HW16()

This function generates the 16-bit CRC value using the hardware CRC module.

### Function prototype:

```
uint16_t FS_CM33_FLASH_HW16(uint32_t startAddress, uint32_t size, uint32_t moduleAddress, uint16_t crcVal);
```

### Function inputs:

*startAddress* - The first address of the tested memory.

*size* - The size of the tested memory.

Invariable memory test

*moduleAddress* - The address of the CRC module.

*crcVal* - The start condition seed. For the first iteration, it is typically a user-defined value. For the next iterations, it is the result of the previous function call.

**Function output:**

*uint16\_t* - The 16-bit CRC value of the memory range (CRC-16-CCITT - normal 0x1021).

**Function performance:**

The function size is 40 B.<sup>1</sup>

The function duration depends on the defined block size. Several examples are shown in the following table:

**Table 7. Duration of FS\_CM33\_FLASH\_HW16() in dependence of tested block size**

Block size (Bytes)	Clock cycles	Execution time (approximately)
0x10	205	2.14 µs
0x20	341	3.55 µs
0x50	749	7.80 µs

**Calling restrictions:**

The function cannot be interrupted by a function that changes the content or setup of the hardware CRC module.

## 5.2.5 FS\_CM33\_FLASH\_SW16()

This function generates the 16-bit CRC value using software.

**Function prototype:**

*uint16\_t FS\_CM33\_FLASH\_SW16(uint32\_t startAddress, uint32\_t size, uint32\_t moduleAddress, uint16\_t crcVal);*

**Function inputs:**

*startAddress* - The first address of the tested memory.

*size* - The size of the tested memory.

*moduleAddress* - It has no effect. It is here only due to the compatibility with the hardware function.

*crcVal* - The start condition seed. For the first iteration, it is typically a user-defined value. For the next iterations, it is the result from the previous function call.

**Function output:**

*uint16\_t* - The 16-bit CRC value of the memory range (CRC-16-CCITT - normal 0x1021).

**Function performance:**

The function size is 54 B.<sup>1</sup>

The function duration depends on the defined block size. Several examples are shown in the following table:<sup>1</sup>

**Table 8. Duration of IEC60730B\_Flash\_SWTest() in dependence of tested block size**

Block size (Bytes)	Clock cycles	Execution time (approximately)
0x4	1907	19.87 µs
0x8	3687	38.41 µs
0x10	9091	94.70 µs

**Calling restrictions:**

None.

## 5.2.6 FS\_CM33\_FLASH\_HW32()

This function generates the 32-bit CRC value using the hardware CRC module.

**Function prototype:**

```
uint32_t FS_CM33_FLASH_HW32(uint32_t startAddress, uint32_t size, uint32_t moduleAddress, uint32_t crcVal);
```

**Function inputs:**

*startAddress* - The first address of the tested memory.

*size* - The size of the tested memory.

*moduleAddress* - The address of the CRC module.

*crcVal* - The start condition seed. For the first iteration, it is typically a user-defined value. For the next iterations, it is the result from the previous function call.

**Function output:**

*uint32\_t* - The 32-bit CRC value of the memory range (CRC-32/MPEG-2 - 0x04C11DB7).

**Function performance:**

The function size is 40 B.<sup>1</sup>

The function duration depends on the defined block size. Several examples are shown in the following table:<sup>1</sup>

**Table 9. Duration of FS\_CM33\_FLASH\_HW32() in dependence of tested block size**

Block size (Bytes)	Clock cycles	Execution time (approximately)
0x10	192	2.00 µs
0x20	336	3.50 µs
0x50	744	7.75 µs

**Calling restrictions:**

The function cannot be interrupted by a function that changes the content or setup of the hardware CRC module.

## 5.2.7 FS\_CM33\_FLASH\_SW32()

This function calculates the 32-bit CRC polynomial (0x04C11DB7) without using hardware.

**Function prototype:**

```
uint32_t FS_CM33_FLASH_SW32(uint32_t startAddress, uint32_t size, uint32_t moduleAddress, uint32_t crcVal);
```

**Function inputs:**

*startAddress* - The first address of the tested memory.

*size* - The size of the tested memory.

*moduleAddress* - It has no effect. It is here only due to the compatibility with the hardware function.

*crcVal* - The start condition seed. For the first iteration, it is typically a user-defined value. For the next iterations, it is the result from the previous function call).

**Function output:**

*uint32\_t* - The 32-bit CRC value of the memory range (CRC-32/MPEG-2 - 0x04C11DB7).

Invariable memory test

**Function performance:**

The function size is 65 B.<sup>1</sup>

The function duration depends on the defined block size. Several examples are shown in the following table:<sup>1</sup>

**Table 10. Duration of FS\_CM33\_FLASH\_SW32() in dependence of tested block size**

Block size (Bytes)	Clock cycles	Execution time (approximately)
0x4	1725	17.97 $\mu$ s
0x8	3405	35.47 $\mu$ s
0x10	8369	87.18 $\mu$ s

**Calling restrictions:**

None.

# Chapter 6

## CPU program counter test

The CPU program counter register test procedure tests the CPU program counter register for the "stuck-at" condition. The program counter register test can be performed once after the MCU reset and also during runtime.

The identification of the safety error is ensured by the specific FAIL return if the CPU program counter register does not work correctly. Assess the return value of the test function. If it is equal to the FAIL return, then the jump into the safety error handling function occurs. The safety error handling function may be specific to the application and it is not a part of our library. The main purpose of this function is to put the application into a safety state.

By contrast to the other CPU registers, the program counter cannot be simply filled with a test pattern. It is necessary to force the CPU (program flow) to access the corresponding address that is testing the pattern to verify the program counter functionality.

The program counter test works without an initialization function. The short function (another object) is written in a separate file. Place this object to an appropriate address in the flash memory by declaring it in the linker configuration file. The test function uses the address of this routine and also the appropriate address in the RAM memory to test the program counter.

The block diagrams for the program counter register tests are shown in the following figure:

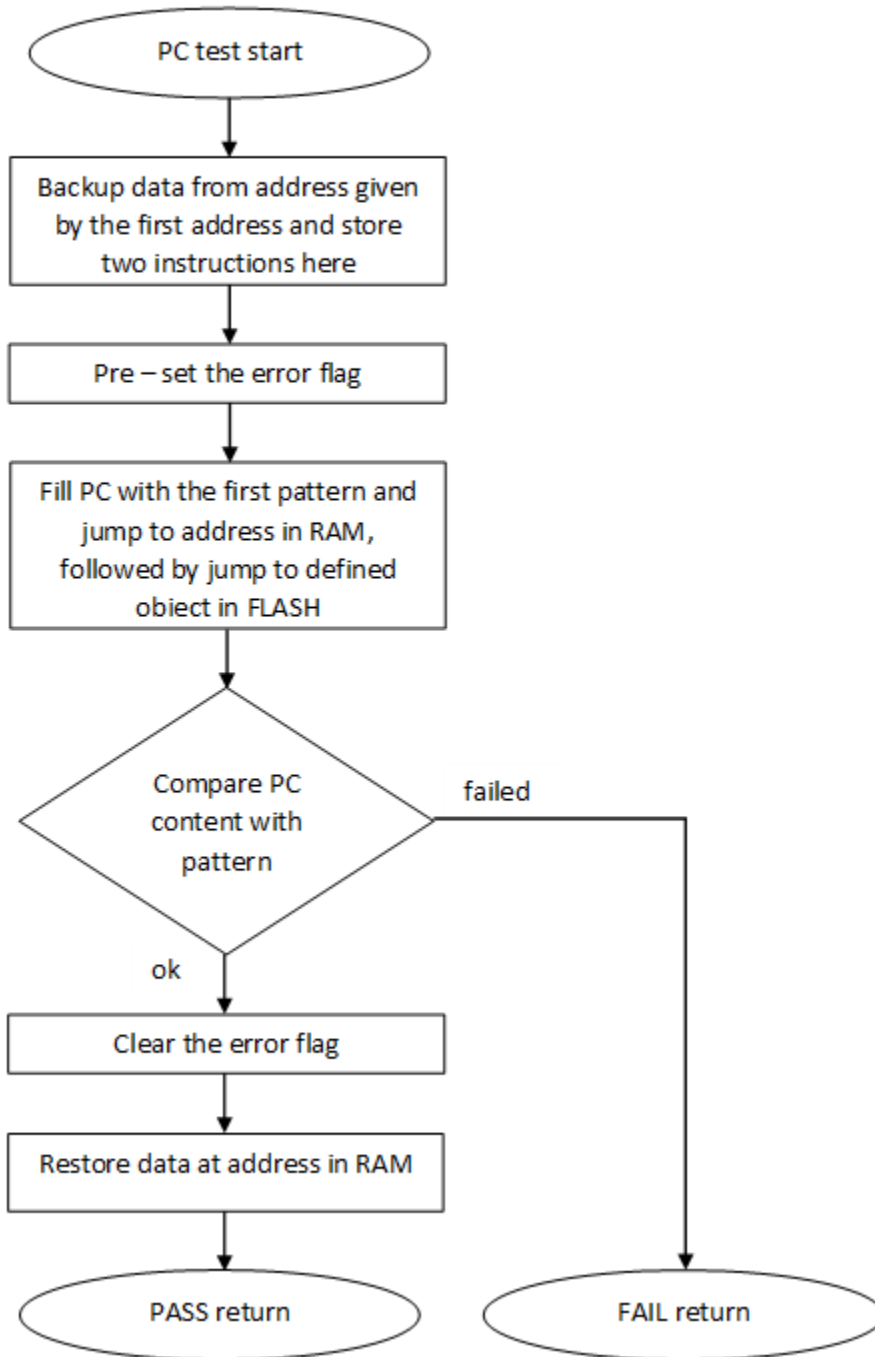


Figure 18. Block diagram for PC\_Test

## 6.1 CPU program counter test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to the IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

Table 11. CPU program counter test in compliance with IEC/UL standards

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
CPU	CPU (1.3 – Programme Counter)	Stuck at	B/R.1	Periodic self test

## 6.2 CPU program counter test implementation

The test functions for the CPU registers are placed in the *iec60730b\_cm33\_pc.S* file and written as assembler functions. The header file with the test patterns and function prototypes is *iec60730b\_cm33\_pc.h*. The *iec60730b.h* and *asm\_mac\_common.h* files are included in the *iec60730b\_cm33\_pc.S* file. Therefore, they must be also placed in the application. For the second test type, place the *iec60730b\_cm33\_pc\_object.S* file to the appropriate address in the flash memory.

### Implementation example of PC test:

The only function that is handled in the application is:

*FS\_CM33\_PC\_Test()*

Place an appropriate pattern as the first input. If needed, call the function more times in a sequence with different patterns. The test pattern must be a real address in the RAM and it must be even-numbered. The *iec60730b\_cm33\_pc\_object.S* file must be placed to an appropriate address in the flash memory.

The following is an example of a function call:

```
#include "iec60730b.h"
extern unsigned long PC_test_flag; /* from Linker configuration file */
const unsigned long Program_Counter_test_flag = (unsigned long)&PC_test_flag;
#define PC_TEST_FLAG ((unsigned long *) Program_Counter_test_flag)

fs_pc_test_result = FS_CM33_PC_Test(0x20000013, FS_PC_object, PC_TEST_FLAG);
if(FS_PC_FAIL == fs_pc_test_result)
    SafetyError();
```

### 6.2.1 FS\_CM33\_PC\_Test()

The program counter register is tested according to the block diagram in [CPU program counter test](#).

#### Function prototype:

*FS\_RESULT FS\_CM33\_PC\_Test(uint32\_t pattern1, tFcn\_pc pObjectFunction, uint32\_t \*pFlag);*

#### Function inputs:

*pattern1* - The address from the RAM memory, adequate as a pattern for the program counter.

*pObjectFunction* - The address of the *FS\_PC\_Object()* function.

*\*pFlag* - The address of the variable/place in the memory used as a flag. If the flag is "0", the test is successful ("1" if the test failed).

#### Function output:

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_PC* - In case of incorrect test execution, *PC\_flag* has a value of "1".

CPU program counter test

**Function performance:**

The function takes approximately 99 cycles (1.03 µs).<sup>1</sup>

The function size is 48 B.<sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

## 6.2.2 FS\_PC\_Object()

This function is internally used by the *FS\_CM33\_PC\_Test()* function. Function is used for performing PC test, it should be called only by *FS\_CM33\_PC\_Test()* function. It should be placed in reliable address - by editing the linker file.

The following example shows how to place the function at the desired address in the linker configuration file for the IAR tool:

```
define symbol __PC_test_start__ = 0x00008FE0;
define symbol __PC_test_end__ = 0x00008FFF;
define region PC_region = mem:[from __PC_test_start__ to __PC_test_end__];
define block PC_TEST { section .text object iec60730b_cm33_pc_object.o};
place in PC_region { block PC_TEST};
```

**Function prototype:**

```
void FS_PC_Object(void);
```

**Function inputs:**

*void*

**Function output:**

*void*

**Function performance:**

The function duration is included in the duration of the *FS\_CM33\_PC\_Test()* function. Its size is 20 bytes.<sup>1</sup>

**Calling restrictions:**

This function is used to perform the PC test, it should be called only by the *FS\_CM33\_PC\_Test()* function.



# Chapter 7

## Variable memory test

The variable memory test for CM33 devices checks the on-chip RAM for DC faults. The application stack area can also be tested. The March C and March X schemes are used as the control mechanisms. Choose whether to use the March C or March X scheme. The handling functions for the after-reset test and the runtime test are different. Both functions must have a backup area defined in the RAM and reserved by the application developer. The size of this area must be at least the same as the size of the tested block. A RAM test is considered destructive. This is because the data from the memory area with the variables, stack area, and functions placed in the RAM are moved away, rewritten multiple times, and then moved back to the original memory area. The test procedure is very sensitive and cannot be interrupted. The block diagrams for the RAM tests are shown in the following figures:

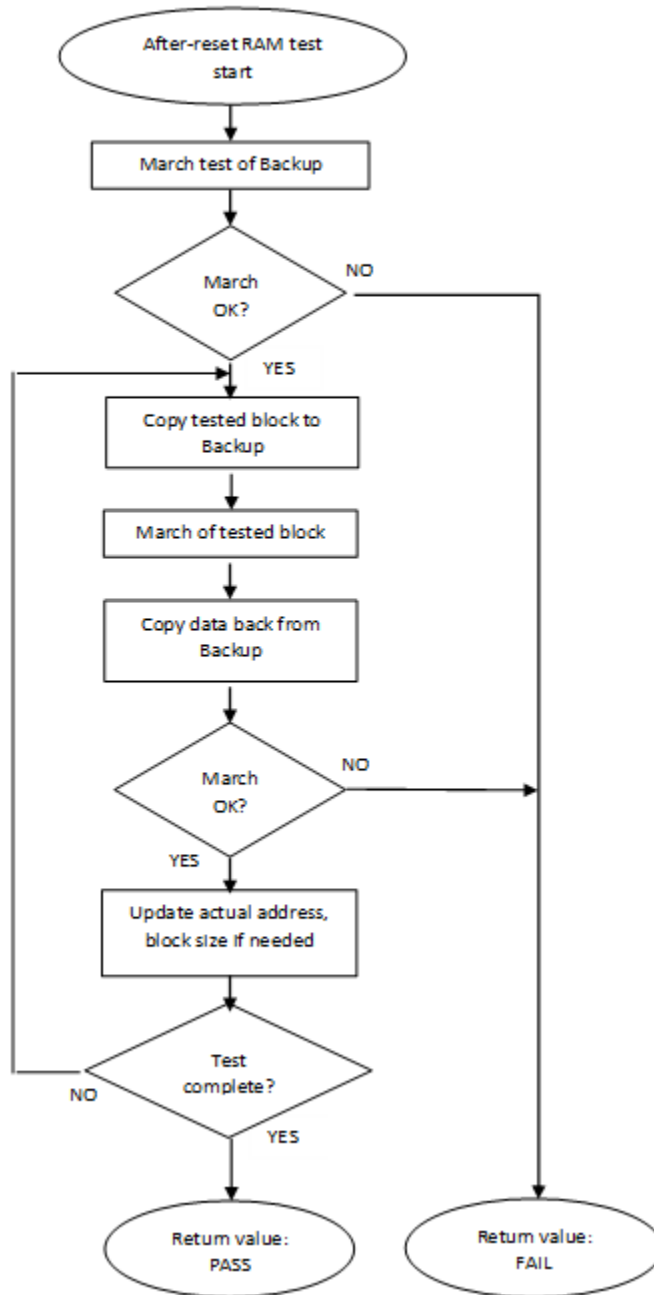


Figure 19. Block diagram for after-reset test of RAM

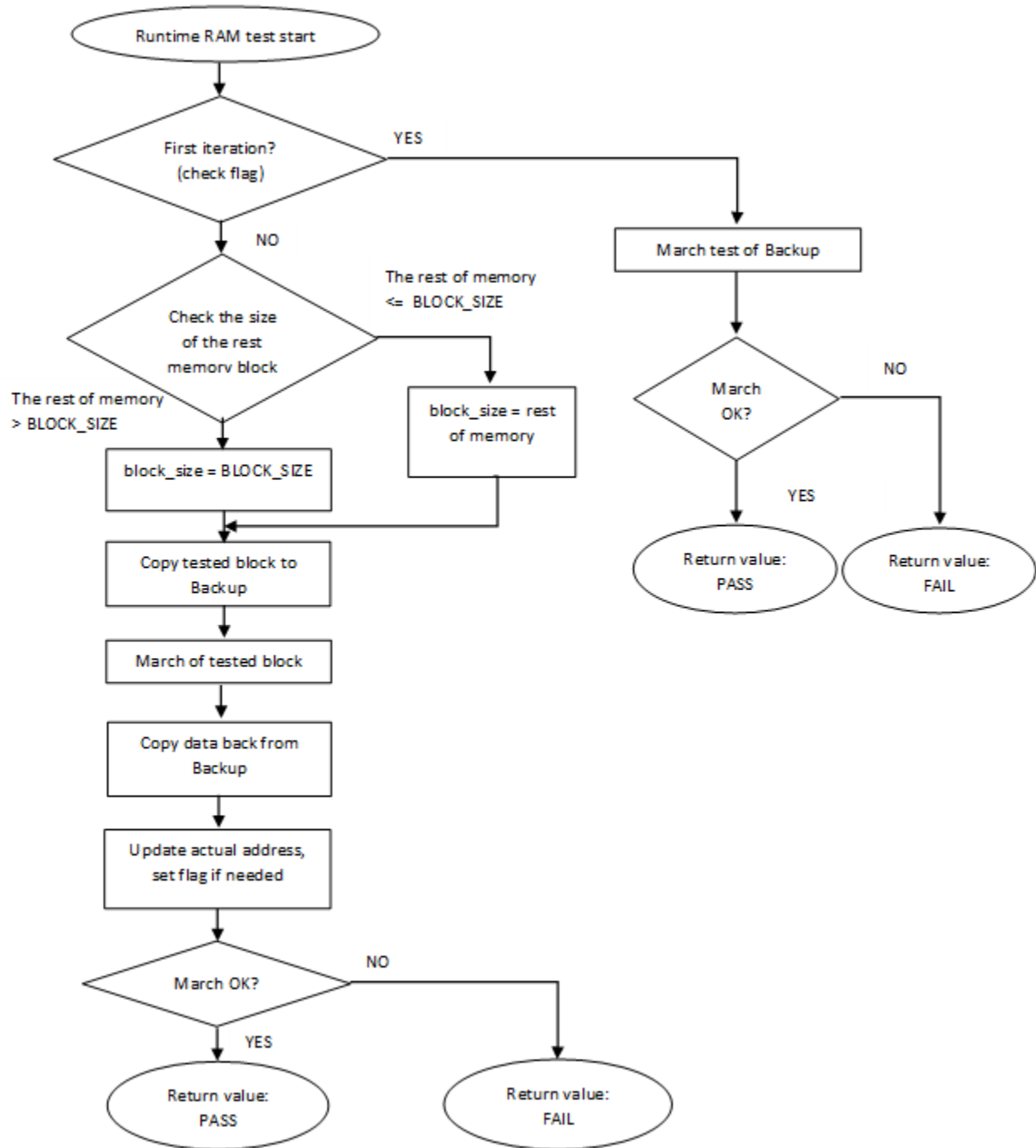


Figure 20. Block diagram for runtime test of RAM

## 7.1 Variable memory test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to to the IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as shown in the following table:

Table 12. Variable memory test in compliance with IEC and UL standards

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
Variable memory	4.2 – Variable memory	DC fault	B/R.1	Periodic self-test using March test

## 7.2 Variable memory test implementation

The test functions for the variable memory (RAM) test are placed in the *FS\_B\_CM33\_ram.S* file and written as assembler functions. The header file with return values and function prototypes is *FS\_B\_CM33\_ram.h*. The *FS\_B\_CM33.h* and *asm\_mac\_common.h* files are included in the *FS\_B\_ram.S* file. Therefore, they must be also placed in the application.

The RAM test consists of the following public functions:

- *FS\_CM33\_RAM\_RuntimeTest()*
- *FS\_CM33\_RAM\_AfterResetTest()*
- *FS\_CM33\_RAM\_SegmentMarchC()*
- *FS\_CM33\_RAM\_SegmentMarchX()*
- *FS\_CM33\_RAM\_CopyToBackup()*
- *FS\_CM33\_RAM\_CopyFromBackup()*

The first two functions provide a complex RAM test. You do not have to work directly with the remaining functions.

### 7.2.1 FS\_CM33\_RAM\_AfterReset()

The after-reset test is done by the *FS\_CM33\_RAM\_AfterReset()* function. This function is called once after the reset, when the execution time is not critical. Reserve free memory space for the backup area. The block size parameter cannot be larger than the size of the backup area. The function firstly checks the backup area. Then the loop begins. Blocks of memory are copied to the backup area and their locations are checked by the respective March test. The data is copied back to the original memory area and the actual address with the block size is updated. This is repeated until the last block of memory is tested. If a DC fault is detected, the function returns a fail pattern. The block diagram is shown in [Figure 19](#).

The following is an example of a function call:

```
#include "iec60730b.h"

if(FS_RAM_FAIL == FS_CM33_RAM_AfterReset(start_address, end_address, block_size, backup_address,
FS_CM33_RAM_SegmentMarchC))
    SafetyError();
```

#### Function prototype:

```
FS_RESULT FS_CM33_RAM_AfterReset(uint32_t startAddress, uint32_t endAddress, uint32_t blockSize, uint32_t
backupAddress, tFcn pMarchType);
```

#### Function inputs:

*startAddress* - The first address of the tested RAM area.

*endAddress* - The address of the first byte after the tested RAM area.

*blockSize* - The tested block size.

*backupAddress* - The address of the backup area.

*\*pMarchType* - The address of the March function (March X or March C).

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_RAM*

**Function performance:**

The function size is 98 B.<sup>1</sup>

The execution time depends on the memory size. It also varies with different block sizes and the March method used.<sup>1</sup>

**Table 13. FS\_CM33\_RAM\_AfterReset duration**

Memory Size (Bytes)	Block S Size (Bytes)	Cycles - March X	Cycles - March C
0x100	0x20	4212	5686
0x100	0x40	3882	5354
0x100	0x80	4042	5708
0x200	0x20	4218	10766
0x200	0x40	3882	9750
0x200	0x80	4042	9770
0x400	0x20	4218	20926
0x400	0x40	3882	18542
0x400	0x80	4042	17878

**Calling restrictions:**

This function is used once after the MCU reset, when the execution time is not critical. It cannot be interrupted. The backup area must be at least the same size as the tested block size defined by the *block\_size* parameter.

## 7.2.2 FS\_CM33\_RAM\_Runtime()

The runtime test is done by the *FS\_CM33\_RAM\_Runtime()* function. Reserve free memory space dedicated for the backup. The block size parameter cannot be larger than the size of the backup area. During the first call, the function checks the backup area. After the call, the blocks of memory are processed in a sequence. They are copied to the backup area and their locations are checked with the respective March test. The data is copied back to the original memory area and the actual address and the block size are updated. This is repeated until the last block of memory is tested. If a DC fault is detected, the function returns a fail pattern. The block diagram is shown in the above figure. This is an example of the function call:

```
#include "iec60730b.h"

if(FS_RAM_FAIL == FS_RESULT FS_CM33_RAM_Runtime(start_address, end_address, &actual_address,
block_size, backup_address, IEC60730B_RAM_SegmentMarchX))
    SafetyError();
```

**Function prototype:**

```
FS_RESULT FS_CM33_RAM_Runtime(uint32_t startAddress, uint32_t endAddress, uint32_t *pActualAddress, uint32_t
blockSize, uint32_t backupAddress, tFcn pMarchType);
```

**Function inputs:**

*startAddress* - The first address of the tested RAM area.

Variable memory test

*endAddress* - The address of the first byte after the tested RAM area.

*\*pActualAddress* - The address of the variable that holds the actual address value.

*blockSize* - The tested block size.

*backupAddress* - The address of the backup area.

*\*pMarchType* - The address of the March function (March X or March C).

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_RAM*

**Function performance:**

The function size is 118 B. <sup>1</sup>

The execution time depends on the block size and it is different for the March C and March X methods. <sup>1</sup>

**Table 14. FS\_CM33\_RAM\_Runtime duration**

Block size (Bytes)	Cycles - March X	Cycles - March C
0x4	198	224
0x8	249	313
0x20	417	577
0x40	641	929

**Calling restrictions:**

The function cannot be interrupted. The backup area must have at least the same size as the tested block size defined by the "block\_size" parameter. The execution time depends on the block size.

## 7.2.3 FS\_CM33\_RAM\_CopyToBackup()

This function copies a block of memory to the dedicated backup area.

**Function prototype:**

*void FS\_CM33\_RAM\_CopyToBackup(uint32\_t startAddress, uint32\_t blockSize, uint32\_t backupAddress);*

**Function inputs:**

*startAddress* - The first address of the source.

*blockSize* - The size of the memory block.

*backupAddress* - The address of the backup area.

**Function output:**

*void*

**Function performance:**

The function size is 20 B. <sup>1</sup>

## 7.2.4 FS\_CM33\_RAM\_CopyFromBackup()

This function copies a block of memory from the backup area to the dedicated place.

**Function prototype:**

```
void FS_CM33_RAM_CopyFromBackup(uint32_t startAddress, uint32_t blockSize, uint32_t backupAddress);
```

**Function inputs:**

*startAddress* - The first address of the destination.

*blockSize* - The size of the memory block.

*backupAddress* - The address of the backup area.

**Function output:**

*void*

**Function performance:**

The function size is 20 B.<sup>1</sup>

## 7.2.5 FS\_CM33\_RAM\_SegmentMarchC()

This function performs a March C test of the memory block that is given by the start address and the block size. The content of the tested memory remains changed after the execution of this function.

**Function prototype:**

```
FS_RESULT FS_CM33_RAM_SegmentMarchC(uint32_t startAddress, uint32_t blockSize);
```

**Function inputs:**

*startAddress* - The first address of the tested memory block.

*blockSize* - The size of the tested memory block.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_RAM*

**Function performance:**

The function size is 124 B.<sup>1</sup>

## 7.2.6 FS\_CM33\_RAM\_SegmentMarchX()

This function performs a March X test of the memory block that is given by the start address and the block size. The content of the tested memory remains changed after the execution of this function.

**Function prototype:**

```
FS_RESULT FS_CM33_RAM_SegmentMarchX(uint32_t startAddress, uint32_t blockSize);
```

**Function inputs:**

*startAddress* - The first address of the tested memory block.

*blockSize* - The size of the tested memory block.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_RAM*

**Function performance:**

Variable memory test

The function size is 114 B.<sup>1</sup>



# Chapter 8

## CPU register test

The CPU register test procedure tests all CM33 CPU registers (except for the program counter register for the "stuck-at" condition). The program counter test is implemented as a standalone safety routine. There is a set of tests performed once after the MCU reset and also during runtime.

The CPU register test functions cover the tests of the following registers:

General-purpose registers:

- R0–R12

Stack pointer registers:

- MSP + MSPLIM (secure/non-secure)
- PSP + PSPLIM (secure/non-secure)

Link register:

- LR

Special registers:

- PRIMASK (secure/non-secure)
- FAULTMASK (secure/non-secure)
- BASEPRI (secure/non-secure)
- CONTROL (secure/non-secure)
- APSR

FPU registers:

- FPSCR
- S0–S31

The identification of safety errors is ensured by the specific FAIL return if some registers have the "stuck-at" fault. Assess the return value of every function. If it is equal to the FAIL return, then a jump into the safety error handling function should occur. The safety error handling function may be specific to the application and it is not a part of the library. The main purpose of this function is to put the application into a safe state.

In some special cases, the error is not reported by the fail return, because it would require the action of a corrupted register. In that case, the function waits in an endless loop for reset.

The principle of the "stuck-at" error test of the CPU registers is to write and compare two test patterns into every register. The content of the register is compared with the constant or value written into another register which was tested before. Most of the time, R0, R1, and R2 are used as auxiliary registers. The patterns are defined to check the logical one and logical zero values in all register bits.

Due to the Arm® TrustZone® support, some core registers are banked between the security states. The Secure (S) or Non-Secure (NS) sets of the corresponding registers are accessible during execution (depending on the current security state). Both register versions are accessible during the S state, but not during the NS state. This is the reason why the NXP Safety Library must be executed in a secure mode. All of the banked registers are listed above.

For the tests of PRIMASK, FAULTMASK, BASEPRI, CONTROL, SP\_main, and SP\_process, the original contents must be backed up. In the case of the FPU register test, the content of FPSCR is backed up. The system register CPACR contains one bit to enable the FPU. Its content is backed up as well. The block diagrams for the respective registers are shown in the following figures:

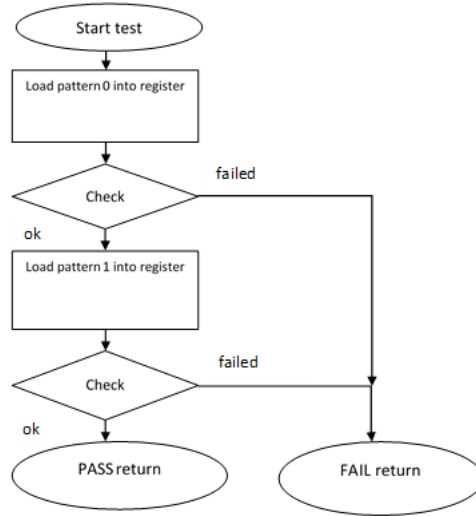


Figure 21. Block diagram for R2-R12 registers test

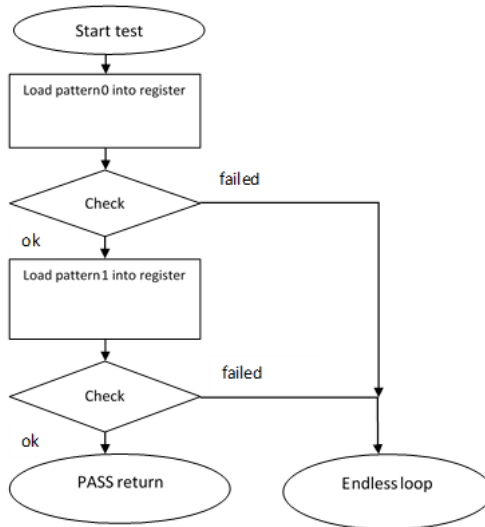


Figure 22. Block diagram for R0, R1, LR, APSR registers test

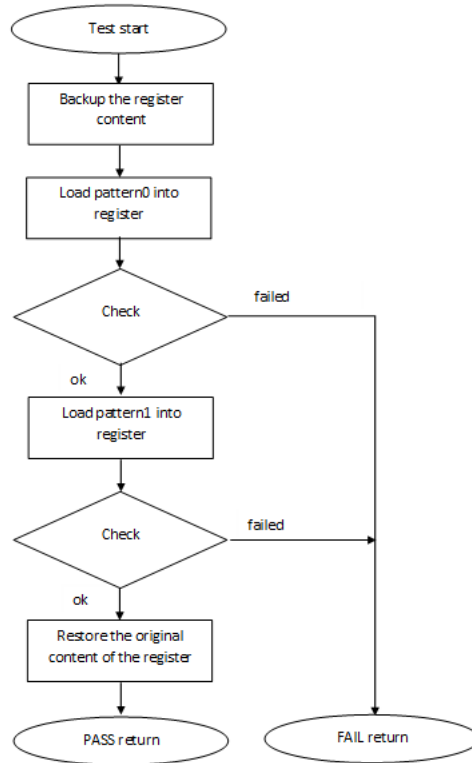


Figure 23. Block diagram for PRIMASK, FAULTMASK, BASEPRI, CONTROL registers test

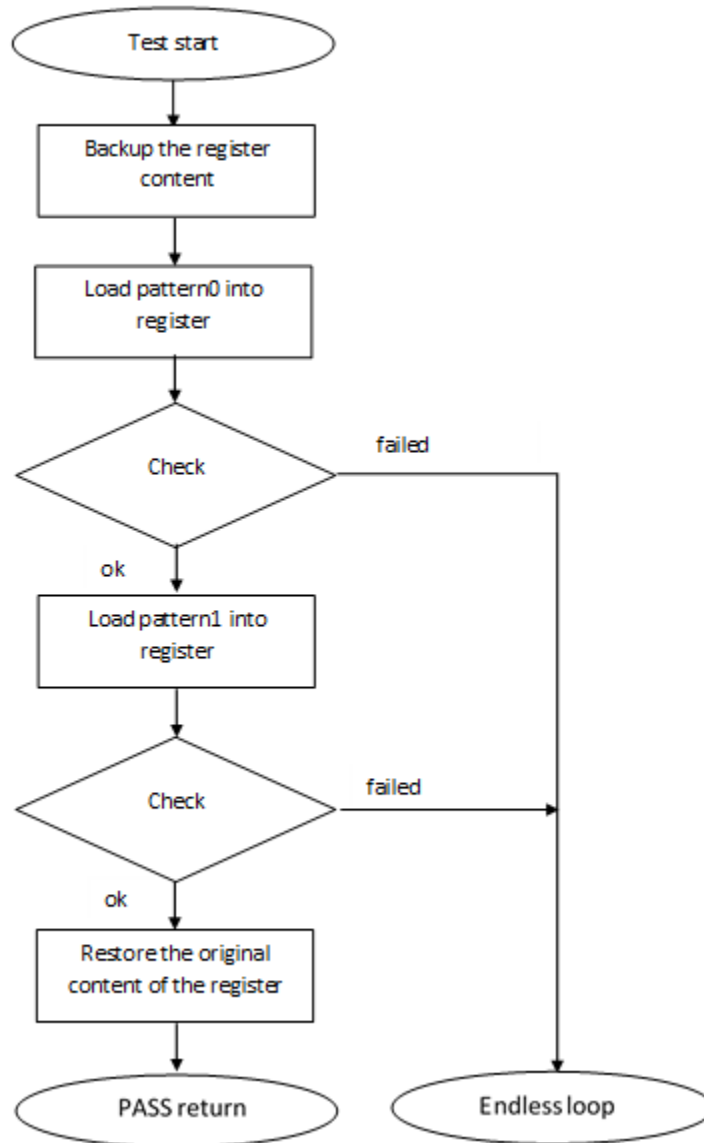


Figure 24. Block diagram for stack pointer registers test

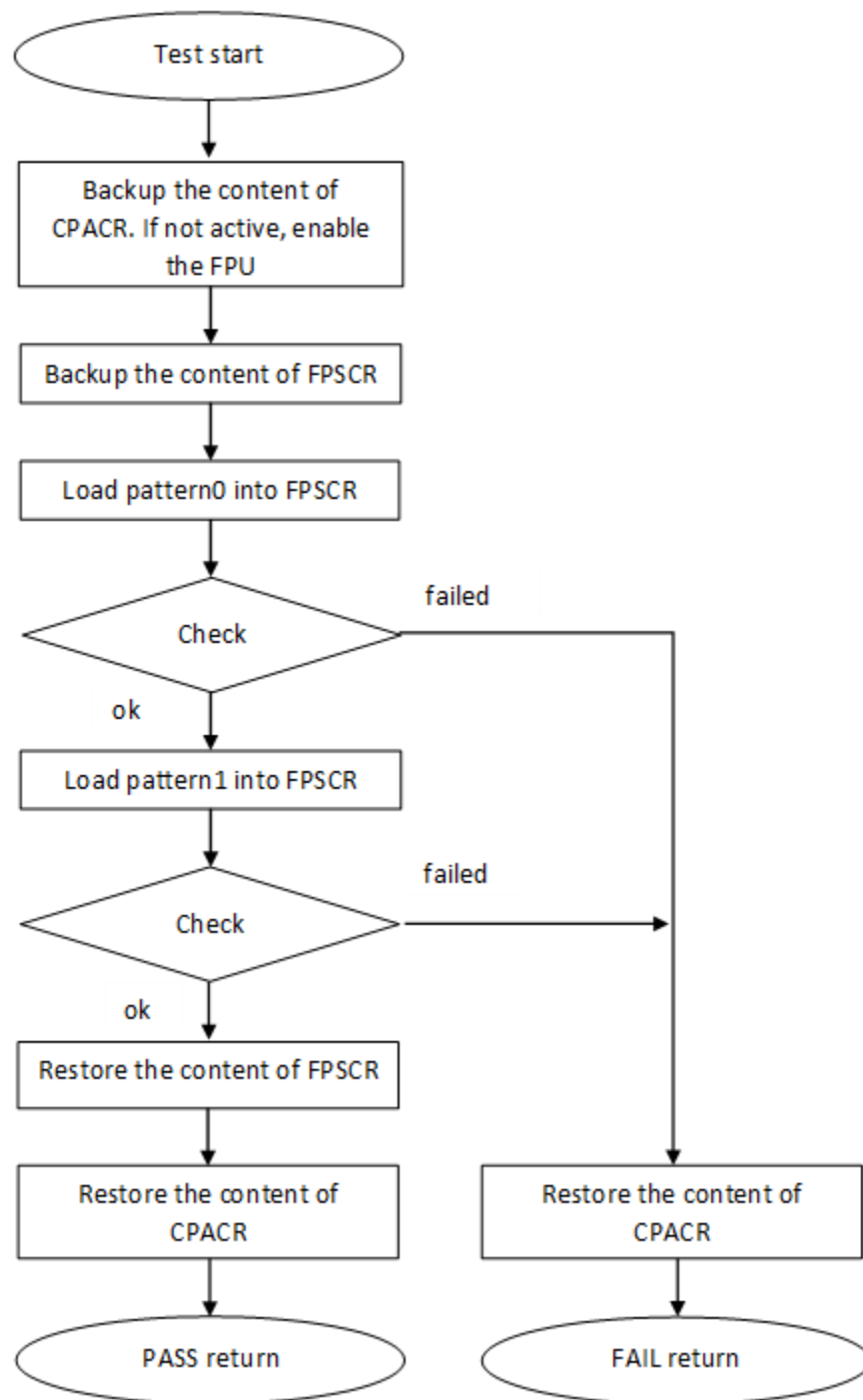


Figure 25. Block diagram for FPSCR register test

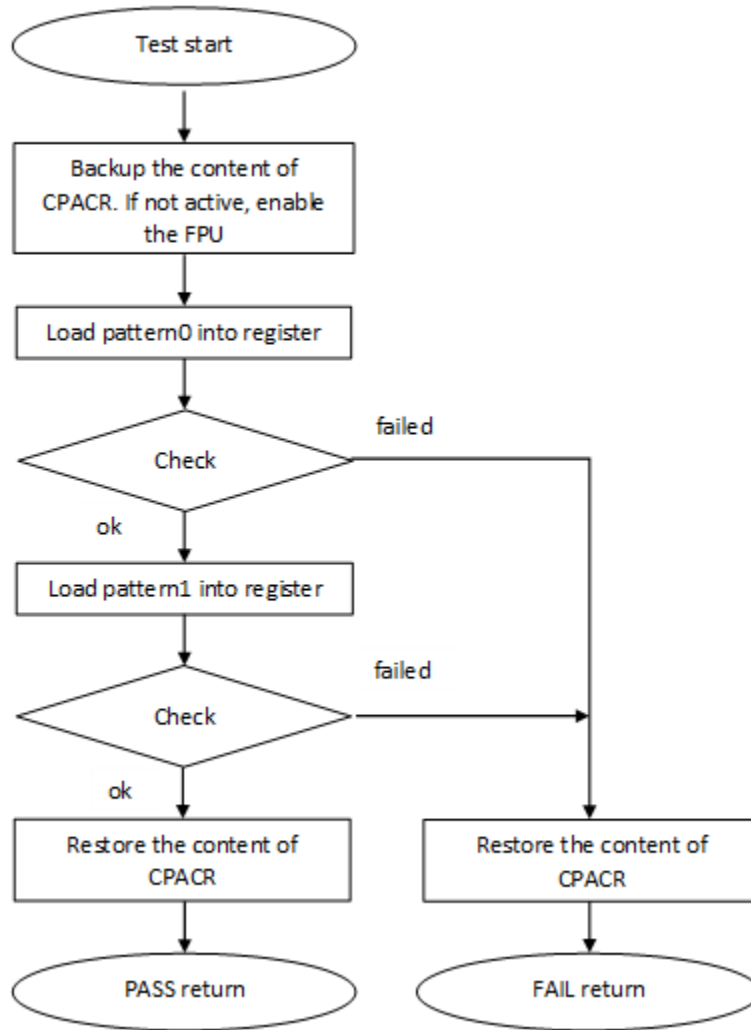


Figure 26. Block diagram for S0-S31 registers test

## 8.1 CPU register test in compliance with IEC/UL standards

The performed overload test fulfils the safety requirements according to the IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

Table 15. CPU registers test in compliance with IEC and UL standards

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
CPU registers test	CPU (1.1 – Registers)	Stuck at	B/R.1	Periodic self test

## 8.2 CPU register test implementation

The test functions for the CPU registers are placed in the *iec60730b\_cm33\_reg.S* file and written as assembler functions. The header file with the return values and function prototypes is *iec60730b\_cm33\_reg.h*.

The *iec60730b.h*, *iec60730b\_core.h*, and *asm\_mac\_common.h* files are included in the *iec60730b\_cm33\_reg.S* file. Therefore, they must be also placed in the application. For devices containing the FPU, *iec60730b\_cm33\_reg\_fpu.S* is an additional file with the tests of FPU-related registers.

The following functions are called to test the corresponding registers:

- FS\_CM33\_CPU\_Register()
- FS\_CM33\_CPU\_NonStackedRegister()
- FS\_CM33\_CPU\_Primask\_S()
- FS\_CM33\_CPU\_Primask\_NS()
- FS\_CM33\_CPU\_SPmain\_S()
- FS\_CM33\_CPU\_SPmain\_NS()
- FS\_CM33\_CPU\_SPmain\_Limit\_S()
- FS\_CM33\_CPU\_SPmain\_Limit\_NS()
- FS\_CM33\_CPU\_SPprocess\_S()
- FS\_CM33\_CPU\_SPprocess\_NS()
- FS\_CM33\_CPU\_SPprocess\_Limit\_S()
- FS\_CM33\_CPU\_SPprocess\_Limit\_NS()
- FS\_CM33\_CPU\_Control()
- FS\_CM33\_CPU\_Control\_S()
- FS\_CM33\_CPU\_Control\_NS()
- FS\_CM33\_CPU\_Special8PriorityLevels\_S()
- FS\_CM33\_CPU\_Special8PriorityLevels\_NS()

Functions with **\_S** postfix are intended to test Secure part of the tested register. Functions with **\_NS** postfix are intended to test Non-Secure part of the tested register. Functions *FS\_CM33\_CPU\_Register()* and *FS\_CM33\_CPU\_NonStackedRegister()* haven't postfix because registers R0-R12, LR and APSR are not banked between security states.

In case that TrustZone is supported on the tested device, CONTROL register is banked between security states. Therefore it must be tested by *FS\_CM33\_CPU\_Control\_S()* and *FS\_CM33\_CPU\_Control\_NS()* functions. But when the TrustZone is not supported, CONTROL register must be tested by *FS\_CM33\_CPU\_Control()* function.

When the device has an FPU (the following functions are placed in the *iec60730b\_cm33\_reg\_fpu.S* file):

- FS\_CM33\_CPU\_Float1()
- FS\_CM33\_CPU\_Float2()

The error detection is recognized by a specific return value, as described in the following chapters. There are several exceptions. If some of the R0, R1, LR, APSR, and SP registers are corrupted, the application is in an endless loop instead of returning an error value. If some of these registers are corrupted, the application is not able to make standard operations to identify the safety error (to compare something, to move out from the function, or to return a value).

The use of functions after the reset and during runtime is the same. Be careful when using functions during runtime, as described in the following sections.

This is an example of a function call:

```
#include "iec60730b.h"
if(FS_CPU_REGISTER_FAIL== FS_CM33_CPU_Register())
    SafetyError();
```

## 8.2.1 FS\_CM33\_CPU\_Control()

This function tests the CONTROL register according to the [Figure 23](#). This function is intended to be executed only on devices without TrustZone support.

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_Control(void);
```

**Test pattern:**

```
CONTROL: 0x00000002, 0x00000004
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_CPU\_CONTROL*

**Function performance:**

The function takes approximately 47 cycles (0.49  $\mu$ s). <sup>1</sup>

The function size is 50 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

This test must be executed only on devices without TrustZone support.

## 8.2.2 FS\_CM33\_CPU\_Control\_NS()

This function tests the CONTROL\_NS (Non-Secure) register according to the [Figure 23](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_Control_NS(void);
```

**Test pattern:**

```
CONTROL_NS: 0x00000002, 0x00000004
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_CPU\_CONTROL*

**Function performance:**

The function takes approximately 37 cycles (0.39  $\mu$ s). <sup>1</sup>

The function size is 52 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the non-secure state.



## 8.2.3 FS\_CM33\_CPU\_Control\_S()

This function tests the CONTROL (secure) register according to the [Figure 23](#).

### Function prototype:

```
FS_RESULT FS_CM33_CPU_Control_S(void);
```

### Test pattern:

CONTROL: 0x0000000A, 0x00000004

### Function inputs:

void

### Function output:

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS
- FS\_FAIL\_CPU\_CONTROL

### Function performance:

The function takes approximately 47 cycles (0.49  $\mu$ s). <sup>1</sup>

The function size is 50 B. <sup>1</sup>

### Calling restrictions:

This function cannot be interrupted.

The core must be in the secure state.

## 8.2.4 FS\_CM33\_CPU\_NonStackedRegister()

This function tests the following CPU registers in a sequence: R8, R9, R10, R11. Each register is tested according to the [Figure 21](#)

### Function prototype:

```
FS_RESULT FS_CM33_CPU_NonStackedRegister(void);
```

### Test patterns for respective registers:

R8 – R11: 0x55555555, 0xAAAAAAAA

### Function inputs:

void

### Function output:

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS
- FS\_FAIL\_CPU\_NONSTACKED\_REGISTER

### Function performance:

The function takes approximately 75 cycles (0.78  $\mu$ s). <sup>1</sup>

The function size is 80 B. <sup>1</sup>

### Calling restrictions:

Can be executed in both the secure and non-secure modes.

## 8.2.5 FS\_CM33\_CPU\_Primask\_NS()

This function tests the PRIMASK\_NS (Non-Secure) register according to the [Figure 23](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_Primask_NS(void);
```

**Test pattern:**

```
PRIMASK: 0x00000001, 0x00000000
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_CPU\_PRIMASK*

**Function performance:**

The function takes approximately 44 cycles (0.46  $\mu$ s). <sup>1</sup>

The function size is 44 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted by an interrupt where the global interrupts are disabled.

The core must be in the non-secure state.

## 8.2.6 FS\_CM33\_CPU\_Primask\_S()

This function tests the PRIMASK\_S (secure) register according to the [Figure 23](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_Primask_S(void);
```

**Test pattern:**

```
PRIMASK: 0x00000001, 0x00000000
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_CPU\_PRIMASK*

**Function performance:**

The function takes approximately 38 cycles (0.40  $\mu$ s). <sup>1</sup>

The function size is 44 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted by an interrupt where the global interrupts are disabled.

The core must be in the secure state.

## 8.2.7 FS\_CM33\_CPU\_Register()

This function tests the following CPU registers in a sequence: R0-R7, R12, LR, APSR. Each register is tested according to the [Figure 21](#) and [Figure 22](#).

### Function prototype:

```
FS_RESULT FS_CM33_CPU_Register(void);
```

### Test patterns for respective registers:

R0–R7, R12, LR: 0x55555555, 0xAAAAAAAA

APSR: 0x50050000, 0xA80A0000

### Function inputs:

void

### Function output:

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS
- FS\_FAIL\_CPU\_REGISTER

If R0, R1, LR, or APSR are corrupted, the function sticks in an endless loop with the interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

### Function performance:

The function takes approximately 201 cycles (2.1  $\mu$ s).<sup>1</sup>

The function size is 204 B.<sup>1</sup>

### Calling restrictions:

Can be executed in both the secure and non-secure modes.

## 8.2.8 FS\_CM33\_CPU\_Special8PriorityLevels\_NS()

This function tests the BASEPRI\_NS and FAULTMASK\_NS (Non-Secure) registers according to the [Figure 23](#).

### Function prototype:

```
FS_RESULT FS_CM33_CPU_Special8PriorityLevels_NS(void);
```

### Test pattern:

BASEPRI: 0xA0, 0x40

FAULTMASK: 0x1, 0x0

### Function inputs:

void

### Function output:

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS
- FS\_FAIL\_CPU\_SPECIAL

### Function performance:

The function takes approximately 81 cycles (0.84  $\mu$ s).<sup>1</sup>

The function size is 88 bytes.<sup>1</sup>

CPU register test

**Calling restrictions:**

This function cannot be interrupted.

For devices with eight priority levels for interrupts.

The core must be in the non-secure state.

## 8.2.9 FS\_CM33\_CPU\_Special8PriorityLevels\_S()

This function tests the BASEPRI and FAULTMASK (secure) registers according to the [Figure 23](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_Special8PriorityLevels_S(void);
```

**Test pattern:**

BASEPRI: 0xA0, 0x40

FAULTMASK: 0x1, 0x0

**Function inputs:**

void

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS
- FS\_FAIL\_CPU\_SPECIAL

**Function performance:**

The function takes approximately 81 cycles (0.84  $\mu$ s).<sup>1</sup>

The function size is 88 B.<sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the secure state.

For devices with eight priority levels for interrupts.

## 8.2.10 FS\_CM33\_CPU\_SPmain\_Limit\_NS()

This function tests the MSPLIM\_NS (Main Stack Pointer Limit, Non-Secure) register according to the [Figure 24](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_SPmain_Limit_NS(void);
```

**Test pattern:**

MSPLIM\_NS: 0x55555550, 0xAAAAAAAA8

**Function inputs:**

void

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- FS\_PASS

If MSPLIM\_NS is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 49 cycles (0.51  $\mu$ s). <sup>1</sup>

The function size is 56 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the non-secure state.

## 8.2.11 FS\_CM33\_CPU\_SPmain\_Limit\_S()

This function tests the MSPLIM (Main Stack Pointer Limit, secure) register according to the [Figure 24](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_SPmain_Limit_S(void);
```

**Test pattern:**

```
MSPLIM: 0x55555550, 0xAAAAAAAA8
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*

If MSPLIM is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 57 cycles (0.59  $\mu$ s). <sup>1</sup>

The function size is 56 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the secure state.

## 8.2.12 FS\_CM33\_CPU\_SPmain\_NS()

This function tests the MSP\_NS (Main Stack Pointer, Non-Secure) register according to the [Figure 24](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_SPmain_NS(void);
```

**Test pattern:**

```
MSP_NS: 0x55555554, 0xAAAAAAAA8
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

CPU register test

- *FS\_PASS*

If MSP\_NS is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 34 cycles (0.35  $\mu$ s). <sup>1</sup>

The function size is 56 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the non-secure state.

## 8.2.13 FS\_CM33\_CPU\_SPmain\_S()

This function tests the MSP (Main Stack Pointer, secure) register according to the [Figure 24](#).

**Function prototype:**

*FS\_RESULT FS\_CM33\_CPU\_SPmain\_S(void);*

**Test pattern:**

*MSP: 0x55555554, 0xAAAAAAA8*

**Function inputs:**

*void*

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*

If the MSP is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 60 cycles (0.63  $\mu$ s). <sup>1</sup>

The function size is 62 B. <sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the secure state.

## 8.2.14 FS\_CM33\_CPU\_SPprocess\_Limit\_NS()

This function tests the PSPLIM\_NS (Process Stack Pointer Limit, Non-Secure) register according to the [Figure 24](#).

**Function prototype:**

*FS\_RESULT FS\_CM33\_CPU\_SPprocess\_Limit\_NS(void);*

**Test pattern:**

*PSPLIM\_NS: 0x55555550, 0xAAAAAAA8*

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*

If the PSPLIM\_NS is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function duration is approximately 49 cycles (0.51  $\mu$ s).<sup>1</sup>

The function size is 56 B.<sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the non-secure state.

## 8.2.15 FS\_CM33\_CPU\_SPprocess\_Limit\_S()

This function tests the PSPLIM (Process Stack Pointer Limit, secure) register according to the [Figure 24](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_SPprocess_Limit_S(void);
```

**Test pattern:**

```
PSPLIM: 0x55555550, 0xAAAAAAAA8
```

**Function inputs:**

*void*

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*

If the PSPLIM is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 57 cycles, including the result comparison (0.59  $\mu$ s).<sup>1</sup>

The function size is 56 B.<sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the secure state.

## 8.2.16 FS\_CM33\_CPU\_SPprocess\_NS()

This function tests the PSP\_NS (Process Stack Pointer, Non-Secure) register according to the [Figure 24](#).

**Function prototype:**

```
FS_RESULT FS_CM33_CPU_SPprocess_NS(void);
```

**Test pattern:**

```
PSP_NS: 0x55555554, 0xAAAAAAAA8
```

**Function inputs:**

*void*

CPU register test

**Function output:**

`typedef uint32_t FS_RESULT;`

- `FS_PASS`

If the PSP\_NS is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 49 cycles, including the result comparison (0.51  $\mu$ s).<sup>1</sup>

The function size is 56 B.<sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the non-secure state.

## 8.2.17 FS\_CM33\_CPU\_SPprocess\_S()

This function tests the PSP (secure) register according to the [Figure 24](#).

**Function prototype:**

`FS_RESULT FS_CM33_CPU_SPprocess_S(void);`

**Test pattern:**

*PSP: 0x55555554, 0xAAAAAAAA8*

**Function inputs:**

*void*

**Function output:**

`typedef uint32_t FS_RESULT;`

- `FS_PASS`

If the PSP is corrupted, the function sticks in an endless loop with interrupts disabled. This state must be observed by another safety mechanism (for example, watchdog).

**Function performance:**

The function takes approximately 57 cycles, including the result comparison (0.59  $\mu$ s).<sup>1</sup>

The function size is 56 B.<sup>1</sup>

**Calling restrictions:**

This function cannot be interrupted.

The core must be in the secure state.

## 8.2.18 FS\_CM33\_CPU\_Float1()

This function checks the FPSCR and S0-S15 registers according to the [Figure 25](#) and [Figure 26](#). Within the function, the FPU is enabled in the CPACR register. At the end of the function, the original content of CPACR is restored.

**Function prototype:**

`FS_RESULT FS_CM33_CPU_Float1(void);`

**Test patterns for respective registers:**

*FPSCR: 0x55400015, 0xA280008A*



*S0-S15: 0x55555555, 0xAAAAAAAA*

**Function inputs:**

*void*

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_CPU\_FLOAT\_1*

**Function performance:**

The function takes approximately 201 cycles (2.1  $\mu$ s). <sup>1</sup>

The function size is 204 B. <sup>1</sup>

**Calling restrictions:**

The core must be in the secure state.

Only for devices with the Floating Point Unit (FPU).

## 8.2.19 FS\_CM33\_CPU\_Float2()

This function checks the S16-S31 registers according to the [Figure 26](#). Within the function, the FPU is enabled in the CPACR register. At the end of the function, the original content of the CPACR is restored.

**Function prototype:**

*FS\_RESULT FS\_CM33\_CPU\_Float2(void);*

**Test patterns for respective registers:**

*S16-S31: 0x55555555, 0xAAAAAAAA*

**Function inputs:**

*void*

**Function output:**

*typedef uint32\_t FS\_RESULT;*

- *FS\_PASS*
- *FS\_FAIL\_CPU\_FLOAT\_2*

**Function performance:**

The function takes approximately 201 cycles (2.1  $\mu$ s). <sup>1</sup>

The function size is 204 B. <sup>1</sup>

**Calling restrictions:**

The core must be in the secure state.

Only for devices with the Floating Point Unit (FPU).

# Chapter 9

## Stack test

This test routine is used to test the overflow and underflow conditions of the application stack. The testing of the "stuck-at" faults in the memory area occupied by the stack is covered by the variable memory test. The overflow or underflow of the stack can occur if the stack is incorrectly controlled, or by defining a very small stack area for the given application.

The principle of the test is to fill an area below and above the stack with a known pattern. Define these areas in the linker configuration file, just like the stack. The initialization function then fills these areas with a pattern defined by the application developer. The pattern must have a value that does not appear elsewhere in the application. The test is performed after the reset and during application runtime in the same way. The purpose is to check if the exact pattern is still written in these areas. If it is not, it is a sign of incorrect stack behavior. If this occurs, the fail return value from the test function must be processed as a safety error.

### 9.1 Stack test in compliance with IEC/UL standards

The stack test is an additional test. It is not directly specified in the IEC60730 annex H table.

### 9.2 Stack test implementation

The test function for the stack and the initialization function are placed in the *IEC60730\_B\_CM33\_stack.S* file and written as assembler functions. The header file with the return values and function prototypes is *IEC60730\_B\_CM33\_stack.h*.

The *IEC60730\_B\_CM33.h* and *asm\_mac\_common.h* files are included in the *IEC60730\_B\_CM33\_stack.S* file. Therefore, they must be also placed in the application. The example for the linker setup, process of initialization, and implementation are shown in the following sections.

#### 9.2.1 Linker setup

The size and placement of the application stack is generally defined in the linker configuration file. Therefore, you must define the areas below and under the stack here as well. There are other methods to achieve this, but only one example is shown here. The size of the areas must be a multiple of 0x4. The minimal size is 0x4.

```
define symbol __ICFEDIT_region_RAM_start__ = 0x1FFFC410;
define symbol __ICFEDIT_region_RAM_end__ = 0x1FFFFFF7;
define symbol __region_RAM2_start__ = 0x20000014;
define symbol __region_RAM2_end__ = 0x20003FDB;
define symbol __ICFEDIT_size_cstack__ = 512;
define exported symbol STACK_TEST_BLOCK_SIZE = 0x10;
define exported symbol STACK_TEST_P_4 = __region_RAM2_end__ - 0x3;
define exported symbol STACK_TEST_P_3 = STACK_TEST_P_4 - STACK_TEST_BLOCK_SIZE + 0x4;
define exported symbol __BOOT_STACK_ADDRESS = STACK_TEST_P_3 - 0x4;
define exported symbol STACK_TEST_P_2 = __BOOT_STACK_ADDRESS - __ICFEDIT_size_cstack__ - 0x4;
define exported symbol STACK_TEST_P_1 = STACK_TEST_P_2 - STACK_TEST_BLOCK_SIZE;
define region RAM_region = mem:[from __ICFEDIT_region_RAM_start__ to __region_RAM2_end__] - mem:[from
STACK_TEST_P_1 size 0x10] - mem:[from STACK_TEST_P_3 size 0x10];

// _____
// |_____| --> STACK_TEST_P_1 ....ADR
```

```

// |_____| ....ADR + 0x4
// |_____| ....ADR + 0x8
// |_____| --> STACK_TEST_P_2 ....ADR + 0xC
// |.....|
// |.....|
// |.....|
// |.. STACK..|
// |.....|
// |.....|
// |.....|
// |.....|
// |_____| --> __BOOT_STACK_ADDRESS
// |_____| --> STACK_TEST_P_3
// |_____|
// |_____|
// |_____| --> STACK_TEST_P_4

```

In the example, the size is set to 0x10. The `STACK_TEST_P_2` and `STACK_TEST_P_3` symbols define the first addresses under and above the stack and they are defined as exported symbols. This means that they are also visible in the application. The areas are not included in the RAM region, so the compiler cannot reserve this place for any variables or other parameters.

## 9.2.2 FS\_CM33\_STACK\_Init()

The purpose of initialization is to fill the defined areas with a given pattern. Put the values from the linker configuration file into the variables. Then define the rest of the parameters needed for the initialization function.

### Example of initialization:

```

#include "iec60730b.h"

extern unsigned long STACK_TEST_P_2;
extern unsigned long STACK_TEST_P_3;

const unsigned long stack_test_first_address = (unsigned long)&STACK_TEST_P_2;
const unsigned long stack_test_second_address = (unsigned long)&STACK_TEST_P_3;
const unsigned long stack_test_pattern = 0x77777777;
const unsigned long stack_test_block_size = 0x10;

```

### Function prototype:

```
void FS_CM33_STACK_Init(uint32_t stackTestPattern, uint32_t firstAddress, uint32_t secondAddress, uint32_t blockSize);
```

### Function inputs:

*stackTestPattern* - The pattern to be written into the areas (for example, 0x77777777).

*firstAddress* - The first address of the block under the stack area.

*secondAddress* - The first address of the block above the stack area.

Stack test

*blockSize* - The size of the areas under and above the stack.

**Function output:**

*void*

**Function performance:**

The function takes approximately 105 cycles (1.10 µs) for a block size of 0x10.<sup>1</sup>

The function size is 26 B.<sup>1</sup>

**Calling restrictions:**

None.

## 9.2.3 FS\_CM33\_STACK\_Test()

The testing procedure is the same after the reset and during runtime. The function checks if the areas are not rewritten with content different than that of the defined pattern. The inputs for the testing functions must be the same as for the initialization function.

**Function prototype:**

```
FS_RESULT FS_CM33_STACK_Test(uint32_t stackTestPattern, uint32_t firstAddress, uint32_t secondAddress, uint32_t blockSize);
```

**Function inputs:**

*stackTestPattern* - The pattern to be checked in the areas (for example, 0x77777777).

*firstAddress* - The first address of the block under the stack area.

*secondAddress* - The first address of the block above the stack area.

*blockSize* - The size of the areas under and above the stack.

**Function output:**

```
typedef uint32_t FS_RESULT;
```

- *FS\_PASS*
- *FS\_FAIL\_STACK*

**Function performance:**

The function takes approximately 139 cycles (1.45 µs) for a block size of 0x10.<sup>1</sup>

The function size is 41 B.<sup>1</sup>

**Calling restrictions:**

None.

# Chapter 10

## Watchdog test

The watchdog test provides the testing of the watchdog timer functionality. The test checks whether the watchdog timer can cause a reset and whether the reset happens at the expected time. Before the start of the test, the watchdog must be configured for use in the respective application. The next step before the test is the setup of the independent device timer, which is used for the watchdog timeout comparison. The first function for watchdog testing is called after that. This function refreshes the watchdog timer, activates the device timer, and captures the device timer counter value during an endless loop. This function should be called only once after the Power-On Reset (POR). After the watchdog reset, the second function must be called. This function should be called after every reset, except for the POR. This function checks whether the captured device timer counter value corresponds to the expected watchdog timeout value. The next check is whether the number of watchdog resets does not exceed the limit value. You can choose what action must be made after an incorrect result. Due to safety requirements, you have limited options for choosing the clock source for the watchdog and the device timer. The first condition is that the watchdog timer clock cannot be the same as the watchdog bus interface clock. Check the device reference manual for the watchdog timer clock source options. The second condition is that the watchdog timer clock cannot be the same as the device timer clock.

### 10.1 Watchdog test in compliance with IEC/UL standards

The watchdog test is not directly specified in the IEC60730 - annex H table, but it partially fulfils the safety requirements according to IEC 60730-1, IEC 60335, UL 60730, and UL 1998 standards, as described in the following table:

**Table 16. Watchdog test in compliance with the standards**

Test	Component	Fault / Error	Software / Hardware Class	Acceptable Measures
Watchdog test	3. Clock	Wrong frequency	B/R.1	Frequency monitoring
Watchdog test	8. Monitoring devices and comparators	Any output outside the static and dynamic functional specification	B/R.1	Tested monitoring

### 10.2 Watchdog test implementation

The test functions for the watchdog are placed in the *iec60730b\_wdg.c* file. The header file is *iec60730b\_wdg.h*. The *iec60730b.h* and *asm\_mac\_common.h* files must be placed in the application as well.

You must have available space in the RAM memory, which is not corrupted after the non-POR.

This memory is used for your variable of the *fs\_wdog\_test* type, which is a structure with three members. It is defined in the *iec60730b\_wdg.h* file.

It is important to configure the watchdog module and the device timer before starting the watchdog test.

The watchdog timer module is different for the supported devices. For a correct function for the corresponding device, see the device implementation chapter.

Ensure the handling of the functions. To identify the source of the reset, use the reset control module. The common configuration is that if an unwanted result is found by the check function, the program stays in an endless loop in the function. This causes the application to stay in the loop of watchdog resets. By entering zero as the fourth input value of the check function, the endless loop is not activated. In that case, ensure that the application is put into a safe state.

The following is an example of the watchdog test implementation (MKV1x):

```
#include "iec60730b.h"
#define WATCHDOG_ON
```

```

#define Watchdog_refresh WDOG_REFRESH = 0xA602;WDOG_REFRESH = 0xB480

extern unsigned long WD_TEST_BACKUP; /* from Linker configuration file */
const unsigned long WD_backup_address = (unsigned long)&WD_TEST_BACKUP;

#define WATCHDOG_TEST_VARIABLES ((WD_Test_Str *) WD_backup_address)

#define WD_TEST_LIMIT_HIGH 3400
#define WD_TEST_LIMIT_LOW 3000
#define ENDLESS_LOOP_ENABLE 1 /* set 1 or 0 */
#define WATCHDOG_RESETS_LIMIT 1000
#define WATCHDOG_TIMEOUT_VALUE 100

MCG_C1 |= MCG_C1_IRCLKEN_MASK; /* MCGIRCLK active */
MCG_C2 &= (~MCG_C2_IRCS_MASK); /* slow reference clock selected */
SIM_SCGC5 |= SIM_SCGC5_LPTMR_MASK; /* enable clock gate to LPTMR */
LPTMR0_CSR = 0; /* time counter mode */
LPTMR0_CSR = LPTMR_CSR_TCF_MASK|LPTMR_CSR_TFC_MASK; /* CNR reset on overflow */
LPTMR0_PSR |= LPTMR_PSR_PBYP_MASK; /* prescaler bypassed, */
LPTMR0_PSR &= (~LPTMR_PSR_PCS_MASK); /* clear prescaler clock */
LPTMR0_PSR |= LPTMR_PSR_PCS(0); /* select the clock input */
LPTMR0_CMR = 0; /* clear the compare register */
LPTMR0_CSR |= LPTMR_CSR_TEN_MASK; /* enable timer */

WatchdogEnable();

if(RCM_SRS0_POR_MASK==(RCM_SRS0_POR_MASK &RCM_SRS0)) /* if POR reset */
{
FS_WDOG_Setup(WATCHDOG_TEST_VARIABLES);
}

if(RCM_SRS0_POR_MASK!=(RCM_SRS0_POR_MASK &RCM_SRS0)) /* if non-POR reset */
{
FS_WDOG_Check(WD_TEST_LIMIT_HIGH, WD_TEST_LIMIT_LOW, WATCHDOG_RESETS_LIMIT,
ENDLESS_LOOP_ENABLE, WATCHDOG_TEST_VARIABLES);
}

```

## 10.2.1 FS\_WDOG\_Setup()

This function clears the reset counter, which is a member of the *fs\_wdog\_test\_t* structure. It refreshes the watchdog to start counting from zero. It starts the LPTMR, which must be configured before the function call occurs. Within the waiting endless loop, the value from the LPTMR is periodically stored in the reserved area in the RAM.

### Function prototype:

```
void FS_WDOG_Setup(fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The watchdog timer and the LPTMR must be configured correctly. A variable of the `fs_wdog_test_t` type must be declared and placed into a reliable place. Interrupts should be disabled.

## 10.2.2 FS\_WDOG\_Setup\_COP()

This function can be used for the MKLxx devices. This function clears the reset counter, which is a member of the `fs_wdog_test_t` structure. It refreshes the watchdog to start counting from zero. It starts the LPTMR, which must be configured before the function call occurs. Within the waiting endless loop, the value from the LPTMR is periodically stored in the reserved area in the RAM.

**Function prototype:**

```
void FS_WDOG_Setup_COP(fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to a structure with the `fs_wdog_test_t` variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The watchdog timer and the LPTMR must be configured correctly. A variable of the `fs_wdog_test_t` type must be declared and placed into a reliable place. Interrupts should be disabled.

## 10.2.3 FS\_WDOG\_Setup\_KE0XZ()

Can be used for the KE0xZ devices. This function clears the reset counter, which is a member of the `fs_wdog_test_t` structure. It refreshes the watchdog to start counting from zero. It starts the RTC, which must be configured before the function call occurs. Within the waiting endless loop, the value from the RTC is periodically stored in the reserved area in the RAM.

**Function prototype:**

```
void FS_WDOG_Setup_KE0XZ(fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

Watchdog test

The watchdog timer and the RTC must be configured correctly. A variable of the `fs_wdog_test_t` type must be declared and placed into a reliable place. Interrupts should be disabled.

## 10.2.4 FS\_WDOG\_Setup\_KE1XF()

Can be used for the MKE1xF devices. This function clears the reset counter, which is a member of the `fs_wdog_test_t` structure. It refreshes the watchdog to start counting from zero. It starts the LPTMR, which must be configured before the function call occurs. Within the waiting endless loop, the value from the LPTMR is periodically stored in the reserved area in the RAM.

### **Function prototype:**

```
void FS_WDOG_Setup_KE1XF(fs_wdog_test_t *pWatchdogBackup);
```

### **Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

### **Function output:**

*void*

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

### **Calling restrictions:**

The watchdog timer and the LPTMR must be configured correctly. A variable of the `fs_wdog_test_t` type must be declared and placed into a reliable place. Interrupts should be disabled.

## 10.2.5 FS\_WDOG\_Setup\_KE1XZ()

This function can be used for the KE1xZ devices. This function clears the reset counter, which is a member of the `fs_wdog_test_t` structure. It refreshes the watchdog to start counting from zero. It starts the LPTMR, which must be configured before the function call occurs. Within the waiting endless loop, the value from the LPTMR is periodically stored in the reserved area in the RAM.

### **Function prototype:**

```
void FS_WDOG_Setup_KE1XZ(fs_wdog_test_t *pWatchdogBackup);
```

### **Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

### **Function output:**

*void*

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

### **Calling restrictions:**

The watchdog timer and the LPTMR must be configured correctly. A variable of the `fs_wdog_test_t` type must be declared and placed into the RAM area that is not overwritten during the application startup. Interrupts should be disabled.

## 10.2.6 FS\_WDOG\_Setup\_WWDT\_LPC\_mrt()

This function can be used for the LPC devices with WWDT and MRT. This function clears the reset counter, which is a member of the `fs_wdog_test_t` structure. It refreshes the watchdog to start counting from zero. It starts the MRT, which must be configured before the function call occurs. Within the waiting endless loop, the value from the MRT is periodically stored in the reserved area in the RAM.

### **Function prototype:**



```
void FS_WDOG_Setup_WWDT_LPC_mrt(fs_wdog_test_t *pWatchdogBackup, uint32_t *pMRTimerBase, uint8_t channel);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with fs\_wdog\_test\_t variables.

*\*pMRTimerBase* - The pointer to the Ctimer used.

*channel* - The channel index of the MRT timer.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The watchdog timer and the MRT must be configured correctly. A variable of the fs\_wdog\_test type must be declared and placed into the RAM area that is not overwritten during application startup. Interrupts should be disabled.

## 10.2.7 FS\_WDOG\_Setup\_WWDT\_LPC()

This function can be used for the LPC devices with WWDT. This function clears the reset counter, which is a member of the fs\_wdog\_test\_t structure. It refreshes the watchdog to start counting from zero. It starts the CTimer, which must be configured before the function call occurs. Within the waiting endless loop, the value from the CTimer is periodically stored in the reserved area in the RAM.

**Function prototype:**

```
void FS_WDOG_Setup_WWDT_LPC(fs_wdog_test_t *pWatchdogBackup, uint32_t *pCtimerBase);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with fs\_wdog\_test\_t variables.

*\*pCtimerBase* - The pointer to the CTIMER base address.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The watchdog timer and the Ctimer must be configured correctly. A variable of the fs\_wdog\_test type must be declared and placed into the RAM area that is not overwritten during application startup. Interrupts should be disabled.

## 10.2.8 FS\_WDOG\_Setup\_RT()

This function can be used for the MIMXRT10xx devices. This function clears the reset counter, which is a member of the fs\_wdog\_test\_t structure. It refreshes the watchdog to start counting from zero. It starts the GPT, which must be configured before the function call occurs. Within the waiting endless loop, the value from the GPT is periodically stored in the reserved area in the RAM.

**Function prototype:**

```
void FS_WDOG_Setup_RT(fs_wdog_test_t *pWatchdogBackup, uint32_t *pGPT);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with fs\_wdog\_test\_t variables.

*\*pGPT* - The pointer to the GPT base address.

Watchdog test

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The watchdog timer and the GPT must be configured correctly. A variable of the `fs_wdog_test` type must be declared and placed into a reliable place. Interrupts should be disabled.

## 10.2.9 FS\_CM0\_WDOG\_Setup\_K32W()

This function can be used for the CM0+ core on MK32W0x devices. This function clears the reset counter, which is a member of the `fs_wdog_test_t` structure. It refreshes the watchdog to start counting from zero. It starts the LPTMR, which must be configured before the function call occurs. Within the waiting endless loop, the value from the LPTMR is periodically stored in the reserved area in the RAM.

**Function prototype:**

```
void FS_CM0_WDOG_Setup_K32W(fs_wdog_test_t *pWatchdogBackup, uint32_t *pWDOG, uint32_t *pLPTMR);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

*\*pWDOG* - The pointer to the WDOG base address.

*\*pLPTMR* - The pointer to the LPTMR base address.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The watchdog timer and the LPTMR must be configured correctly. The variable of the `fs_wdog_test` type must be declared and placed into a reliable place. Interrupts should be disabled.

## 10.2.10 FS\_CM4\_WDOG\_Setup\_K32W()

This function can be used for the CM4 core of MK32W0x devices. This function compares the captured value of the LPTMR counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. With the `endless_loop_enable` parameter, the endless loop within the function is enabled or disabled (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit the limit values.
- The watchdog resets exceed the defined limit value.

**Function prototype:**

```
void FS_CM4_WDOG_Setup_K32W(fs_wdog_test_t *pWatchdogBackup, uint32_t *pWDOG, uint32_t *pLPTMR);
```

**Function inputs:**

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

*\*pWDOG* - The pointer to the WDOG base address.

*\*pLPTMR* - The pointer to the LPTMR base address.

**Function output:***void***Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.11 FS\_WDOG\_Check()

This function can be used for the MKV1x and MKLxx devices. This function compares the captured value of the LPTMR counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. With the `endless_loop_enable` parameter, the endless loop within the function is enabled or disabled, (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit the limit values.
- The watchdog resets exceed the defined limit value.

**Function prototype:**

```
void FS_WDOG_Check(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable, fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for watchdog resets.

*endlessLoopEnable* - Enables or disables the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

**Function output:***void***Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.12 FS\_WDOG\_Check\_KE0XZ()

This function can be used for MKE0XZ devices. This function compares the captured value of the RTC counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. The endless loop within the function is enabled or disabled with the `endless_loop_enable` parameter (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceed the defined limit value.

**Function prototype:**

Watchdog test

```
void FS_WDOG_Check_KE0XZ(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable, fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for the watchdog resets.

*endlessLoopEnable* - Enable or disable the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with fs\_wdog\_test\_t variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.13 FS\_WDOG\_Check\_KE1XF()

This function can be used for the KE1xF devices. This function compares the captured value of the LPTMR counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, wd\_test\_uncomplete\_flag is set. The endless loop within the function is enabled or disabled with the endless\_loop\_enable parameter (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceed the defined limit value.

**Function prototype:**

```
void FS_WDOG_Check_KE1XF(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable, fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for the watchdog resets.

*endlessLoopEnable* - Enable or disable the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with fs\_wdog\_test\_t variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is mentioned in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.14 FS\_WDOG\_Check\_KE1XZ()

This function can be used for MKE1xZ devices. This function compares the captured value of the LPTMR counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. The endless loop within the function is enabled or disabled with the `endless_loop_enable` parameter (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceed the defined limit value.

### Function prototype:

```
void FS_WDOG_Check_KE1XZ(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable,
fs_wdog_test_t *pWatchdogBackup);
```

### Function inputs:

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for watchdog resets.

*endlessLoopEnable* - Enable or disable the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

### Function output:

*void*

### Function performance:

The information about the function performance is in [Core self-test library – source code version](#).

### Calling restrictions:

The respective setup function must be executed first.

## 10.2.15 FS\_WDOG\_Check\_WWDT\_LPC()

This function can be used for the LPC8xx devices. This function compares the captured value of the target counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. The endless loop within the function is enabled or disabled with the `endless_loop_enable` parameter (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceed the defined limit value.

### Function prototype:

```
void FS_WDOG_Check_WWDT_LPC(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable,
fs_wdog_test_t *pWatchdogBackup);
```

### Function inputs:

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for watchdog resets.

*endlessLoopEnable* - Enable or disable endless loop within the function.

Watchdog test

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.16 FS\_WDOG\_Check\_RT()

This function can be used for MIMXRT10xx devices. This function compares the captured value of the GPT counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. The endless loop within the function is enabled or disabled with the `endless_loop_enable` parameter (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit the limit values.
- The watchdog resets exceed the defined limit value.

**Function prototype:**

*void FS\_WDOG\_Check\_RT(uint32\_t limitHigh, uint32\_t limitLow, uint32\_t limitResets, bool\_t endlessLoopEnable, fs\_wdog\_test\_t \*pWatchdogBackup);*

**Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for the watchdog resets.

*endlessLoopEnable* - Enable or disable the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.17 FS\_CM0\_WDOG\_Check\_K32W()

This function can be used for the CM0+ core on MK32W0x devices. This function compares the captured value of the LPTMR counter with pre-calculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, the `wd_test_uncomplete_flag` is set. With the `endless_loop_enable` parameter, the endless loop within the function is enabled or disabled (by setting it to 1 or 0). If it is enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceed the defined limit value.

**Function prototype:**

```
void FS_CM0_WDOG_Check_K32W(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable,
fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for the watchdog resets.

*endlessLoopEnable* - Enables or disables the endless loop within the function.

*\*pWatchdogBackup* - The pointer to a structure with the fs\_wdog\_test\_t variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.18 FS\_CM4\_WDOG\_Check\_K32W()

This function can be used for the CM4 core of MK32W0x devices. This function compares the captured value of the LPTMR counter with pre-calculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, the wd\_test\_uncomplete\_flag is set. With the endless\_loop\_enable parameter, the endless loop within the function is enabled or disabled (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceeds the defined limit value.

**Function prototype:**

```
void FS_CM4_WDOG_Check_K32W(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t endlessLoopEnable,
fs_wdog_test_t *pWatchdogBackup);
```

**Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for the watchdog resets.

*endlessLoopEnable* - Enable or disable the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with fs\_wdog\_test\_t variables.

**Function output:**

*void*

**Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

**Calling restrictions:**

The respective setup function must be executed first.

## 10.2.19 FS\_WDOG\_Check\_WWDT\_LPC55SXX()

This function can be used for the LPC55Sxx devices. This function compares the captured value of the target counter with precalculated limit values and checks whether the watchdog reset counter overflows. If the function is called after a non-watchdog reset, `wd_test_uncomplete_flag` is set. The endless loop within the function is enabled or disabled with the `endless_loop_enable` parameter (by setting it to 1 or 0). If enabled, the function ends up in an endless loop under these conditions:

- Entering after non-watchdog or non-POR resets.
- The counter from the watchdog test does not fit within the limit values.
- The watchdog resets exceed the defined limit value.

### **Function prototype:**

```
void FS_WDOG_Check_WWDT_LPC55SXX(uint32_t limitHigh, uint32_t limitLow, uint32_t limitResets, bool_t  
endlessLoopEnable, fs_wdog_test_t *pWatchdogBackup);
```

### **Function inputs:**

*limitHigh* - The precalculated limit value for the reference counter.

*limitLow* - The precalculated limit value for the reference counter.

*limitResets* - The limit value for watchdog resets.

*endlessLoopEnable* - Enable or disable the endless loop within the function.

*\*pWatchdogBackup* - The pointer to the structure with `fs_wdog_test_t` variables.

### **Function output:**

*void*

### **Function performance:**

The information about the function performance is in [Core self-test library – source code version](#).

### **Calling restrictions:**

The respective setup function must be executed first.





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